16-bit Proprietary Microcontroller F²MC-16FX MB96680 Series

MB96F683R/A, MB96F685R/A

DESCRIPTION

MB96680 series is based on FUJITSU's advanced $F^2MC-16FX$ architecture (16-bit with instruction pipeline for RISC-like performance). The CPU uses the same instruction set as the established $F^2MC-16LX$ family thus allowing for easy migration of $F^2MC-16LX$ Software to the new $F^2MC-16FX$ products. $F^2MC-16FX$ product improvements compared to the previous generation include significantly improved performance - even at the same operation frequency, reduced power consumption and faster start-up time.

For high processing speed at optimized power consumption an internal PLL can be selected to supply the CPU with up to 32MHz operation frequency from an external 4MHz to 8MHz resonator. The result is a minimum instruction cycle time of 31.2ns going together with excellent EMI behavior. The emitted power is minimized by the on-chip voltage regulator that reduces the internal CPU voltage. A flexible clock tree allows selecting suitable operation frequencies for peripheral resources independent of the CPU speed.

Note: F²MC is the abbreviation of FUJITSU Flexible Microcontroller.

FUJITSU SEMICONDUCTOR provides information facilitating product development via the following website. The website contains information useful for customers.

http://edevice.fujitsu.com/micom/en-support/



FEATURES

- Technology
 - 0.18µm CMOS
- CPU
 - F²MC-16FX CPU
 - Optimized instruction set for controller applications
 - (bit, byte, word and long-word data types, 23 different addressing modes, barrel shift, variety of pointers) • 8-byte instruction queue
 - Signed multiply (16-bit × 16-bit) and divide (32-bit/16-bit) instructions available

• System clock

- On-chip PLL clock multiplier (×1 to ×8, ×1 when PLL stop)
- 4MHz to 8MHz crystal oscillator
- (maximum frequency when using ceramic resonator depends on Q-factor)
- Up to 8MHz external clock for devices with fast clock input feature
- 32.768kHz subsystem quartz clock 100kHz/2MHz internal RC clock for quick and safe startup, clock stop detection function, watchdog
- Clock source selectable from mainclock oscillator, subclock oscillator and on-chip RC oscillator, independently for CPU and 2 clock domains of peripherals
- The subclock oscillator is enabled by the Boot ROM program controlled by a configuration marker after a Power or External reset
- Low Power Consumption 13 operating modes (different Run, Sleep, Timer, Stop modes)

• On-chip voltage regulator

Internal voltage regulator supports a wide MCU supply voltage range (Min=2.7V), offering low power consumption

Low voltage detection function

Reset is generated when supply voltage falls below programmable reference voltage

Code Security

Protects Flash Memory content from unintended read-out

• DMA

Automatic transfer function independent of CPU, can be assigned freely to resources

Interrupts

- Fast Interrupt processing
- 8 programmable priority levels
- Non-Maskable Interrupt (NMI)

• CAN

- Supports CAN protocol version 2.0 part A and B
- ISO16845 certified
- Bit rates up to 1Mbps
- 32 message objects
- Each message object has its own identifier mask
- Programmable FIFO mode (concatenation of message objects)
- Maskable interrupt
- Disabled Automatic Retransmission mode for Time Triggered CAN applications
- Programmable loop-back mode for self-test operation

• USART

- Full duplex USARTs (SCI/LIN)
- Wide range of baud rate settings using a dedicated reload timer
- Special synchronous options for adapting to different synchronous serial protocols
- LIN functionality working either as master or slave LIN device
- Extended support for LIN-Protocol to reduce interrupt load

• |²C

- Up to 400kbps
- Master and Slave functionality, 7-bit and 10-bit addressing

• A/D converter

- SAR-type
- 8/10-bit resolution
- Signals interrupt on conversion end, single conversion mode, continuous conversion mode, stop conversion mode, activation by software, external trigger, reload timers and PPGs
- Range Comparator Function
- Scan Disable Function
- ADC Pulse Detection Function

Source Clock Timers

Three independent clock timers (23-bit RC clock timer, 23-bit Main clock timer, 17-bit Sub clock timer)

• Hardware Watchdog Timer

- Hardware watchdog timer is active after reset
- Window function of Watchdog Timer is used to select the lower window limit of the watchdog interval
- Reload Timers
 - 16-bit wide
 - Prescaler with $1/2^1$, $1/2^2$, $1/2^3$, $1/2^4$, $1/2^5$, $1/2^6$ of peripheral clock frequency
 - Event count function

• Free-Running Timers

- Signals an interrupt on overflow
- Prescaler with 1, $1/2^1$, $1/2^2$, $1/2^3$, $1/2^4$, $1/2^5$, $1/2^6$, $1/2^7$, $1/2^8$ of peripheral clock frequency

• Input Capture Units

- 16-bit wide
- Signals an interrupt upon external event
- Rising edge, Falling edge or Both (rising & falling) edges sensitive

• Programmable Pulse Generator

- 16-bit down counter, cycle and duty setting registers
- Can be used as 2×8 -bit PPG
- Interrupt at trigger, counter borrow and/or duty match
- PWM operation and one-shot operation
- Internal prescaler allows 1, 1/4, 1/16, 1/64 of peripheral clock as counter clock or of selected Reload timer underflow as clock input
- Can be triggered by software or reload timer
- Can trigger ADC conversion
- Timing point capture



• Stepping Motor Controller

- Stepping Motor Controller with integrated high current output drivers
- Four high current outputs for each channel
- Two synchronized 8/10-bit PWMs per channel
- Internal prescaling for PWM clock: 1, 1/4, 1/5, 1/6, 1/8, 1/10, 1/12, 1/16 of peripheral clock
- Dedicated power supply for high current output drivers

LCD Controller

- LCD controller with up to 4COM × 32SEG
- Internal or external voltage generation
- Duty cycle: Selectable from options: 1/2, 1/3 and 1/4
- Fixed 1/3 bias
- Programmable frame period
- Clock source selectable from four options (main clock, peripheral clock, subclock or RC oscillator clock)
- Internal divider resistors or external divider resistors
- On-chip data memory for display
- LCD display can be operated in Timer Mode
- Blank display: selectable
- All SEG, COM and V pins can be switched between general and specialized purposes

Sound Generator

- 8-bit PWM signal is mixed with tone frequency from 16-bit reload counter
- PWM clock by internal prescaler: 1, 1/2, 1/4, 1/8 of peripheral clock

• Real Time Clock

- Operational on main oscillation (4MHz), sub oscillation (32kHz) or RC oscillation (100kHz/2MHz)
- Capable to correct oscillation deviation of Sub clock or RC oscillator clock (clock calibration)
- Read/write accessible second/minute/hour registers
- Can signal interrupts every half second/second/minute/hour/day
- Internal clock divider and prescaler provide exact 1s clock

External Interrupts

- Edge or Level sensitive
- Interrupt mask bit per channel
- Each available CAN channel RX has an external interrupt for wake-up
- Selected USART channels SIN have an external interrupt for wake-up

Non Maskable Interrupt

- Disabled after reset, can be enabled by Boot-ROM depending on ROM configuration block
- Once enabled, can not be disabled other than by reset
- High or Low level sensitive
- Pin shared with external interrupt 0

• I/O Ports

- Most of the external pins can be used as general purpose I/O
- All push-pull outputs (except when used as I^2C SDA/SCL line)
- Bit-wise programmable as input/output or peripheral signal
- Bit-wise programmable input enable
- One input level per GPIO-pin (either Automotive or CMOS hysteresis)
- Bit-wise programmable pull-up resistor

• Built-in On Chip Debugger (OCD)

- One-wire debug tool interface
- Break function:
 - Hardware break: 6 points (shared with code event)
 - Software break: 4096 points
- Event function
 - Code event: 6 points (shared with hardware break)
 - Data event: 6 points
 - Event sequencer: 2 levels + reset
- Execution time measurement function
- Trace function: 42 branches
- Security function

• Flash Memory

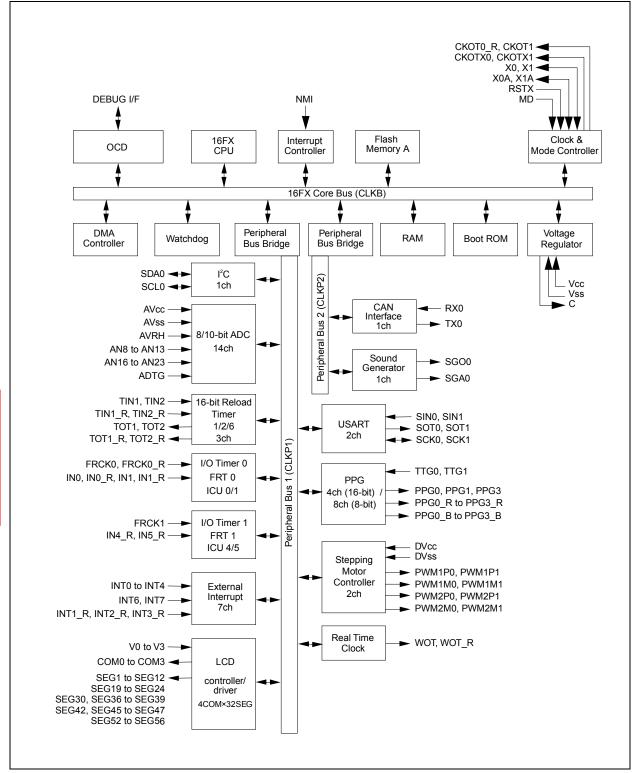
- Dual operation flash allowing reading of one Flash bank while programming or erasing the other bank
- Command sequencer for automatic execution of programming algorithm and for supporting DMA for programming of the Flash Memory
- Supports automatic programming, Embedded Algorithm
- Write/Erase/Erase-Suspend/Resume commands
- A flag indicating completion of the automatic algorithm
- Erase can be performed on each sector individually
- Sector protection
- Flash Security feature to protect the content of the Flash
- Low voltage detection during Flash erase or write

■ PRODUCT LINEUP

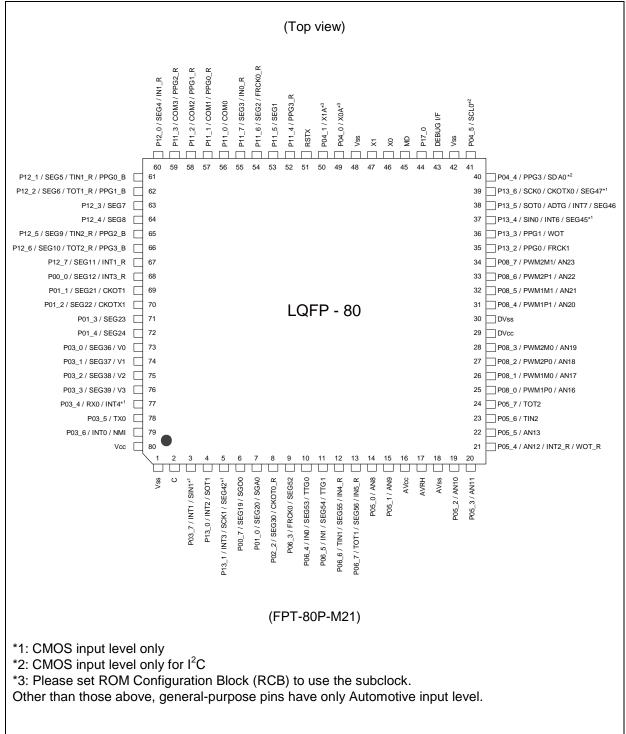
Features			MB96680	Remark
Product Type			Flash Memory Product	
Subclock			Subclock can be set by software	
Dual Operation Flash Memory RAM		-		
64	.5KB + 32KB	4KB	MB96F683R, MB96F683A	Product Options
				R: MCU with CAN
128	8.5KB + 32KB	4KB	MB96F685R, MB96F685A	A: MCU without CAN
Package			LQFP-80 FPT-80P-M21	
DMA			2ch	
USART			2ch	LIN-USART 0/1
	with automatic LIN-H transmission/reception		Yes (only 1ch)	LIN-USART 0
	with 16 byte RX- and TX-FIFO		No	
I ² C			lch	$I^2C 0$
8/10-bit A	/D Converter		14ch	AN 8 to 13/16 to 23
	with Data Buffer		No	
	with Range Comparat	or	Yes	
	with Scan Disable		Yes	
	with ADC Pulse Dete	ction	Yes	
16-bit Rel	oad Timer (RLT)		3ch	RLT 1/2/6
	e-Running Timer (FRT	')	2ch	FRT 0/1
		/	4ch	ICU 0/1/4/5
16-bit Inp	ut Capture Unit (ICU)		(2 channels for LIN-USART)	(ICU 0/1 for LIN-USART
8/16-bit Programmable Pulse Generator (PPG) with Timing point capture with Start delay with Ramp		4ch (16-bit) / 8ch (8-bit)	PPG 0 to 3	
		Yes		
		No		
		No		
CAN Inte	rface		1ch	CAN 0 32 Message Buffers
Stepping 1	Motor Controller (SMC	C)	2ch	SMC 0/1
External I	nterrupts (INT)		7ch	INT 0 to 7
	kable Interrupt (NMI)		lch	
	nerator (SG)		1ch	SG 0
LCD Controller		4COM × 32SEG	COM 0 to 3 SEG 1 to 12/19 to 24/ 30/36 to 39/42/45 to 47/ 52 to 56	
Real Time	e Clock (RTC)		1ch	
I/O Ports		63 (Dual clock mode) 65 (Single clock mode)		
Clock Calibration Unit (CAL)		1ch		
	tput Function		2ch	
	age Detection Function		Yes	Low voltage detection function can be disabled by software
Hardware	Watchdog Timer		Yes	
	RC-oscillator		Yes	
· · ·	Debugger		Yes	

Note: All signals of the peripheral function in each product cannot be allocated by limiting the pins of package. It is necessary to use the port relocate function of the general I/O port according to your function use.

BLOCK DIAGRAM



■ PIN ASSIGNMENT



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■ PIN DESCRIPTION

Pin name	Feature	Description			
ADTG	ADC	A/D converter trigger input pin			
ANn	ADC	A/D converter channel n input pin			
AVcc	Supply	Analog circuits power supply pin			
AVRH	ADC	A/D converter high reference voltage input pin			
AVss	Supply	Analog circuits power supply pin			
С	Voltage regulator	Internally regulated power supply stabilization capacitor pin			
CKOTn	Clock Output function	Clock Output function n output pin			
CKOTn_R	Clock Output function	Relocated Clock Output function n output pin			
CKOTXn	Clock Output function	Clock Output function n inverted output pin			
COMn	LCD	LCD Common driver pin			
DEBUG I/F	OCD	On Chip Debugger input/output pin			
DVcc	Supply	SMC pins power supply			
DVss	Supply	SMC pins power supply			
FRCKn	Free-Running Timer	Free-Running Timer n input pin			
FRCKn_R	Free-Running Timer	Relocated Free-Running Timer n input pin			
INn	ICU	Input Capture Unit n input pin			
INn_R	ICU	Relocated Input Capture Unit n input pin			
INTn	External Interrupt	External Interrupt n input pin			
INTn_R	External Interrupt	Relocated External Interrupt n input pin			
MD	Core	Input pin for specifying the operating mode			
NMI	External Interrupt	Non-Maskable Interrupt input pin			
Pnn_m	GPIO	General purpose I/O pin			
PPGn	PPG	Programmable Pulse Generator n output pin (16bit/8bit)			
PPGn_R	PPG	Relocated Programmable Pulse Generator n output pin (16bit/8bit)			
PPGn_B	PPG	Programmable Pulse Generator n output pin (16bit/8bit)			
PWMn	SMC	SMC PWM high current output pin			
RSTX	Core	Reset input pin			
RXn	CAN	CAN interface n RX input pin			
SCKn	USART	USART n serial clock input/output pin			
SCLn	I ² C	I ² C interface n clock I/O input/output pin			
SDAn	I ² C	I ² C interface n serial data I/O input/output pin			
SEGn	LCD	LCD Segment driver pin			
SGAn	Sound Generator	Sound Generator amplitude output pin			
SGOn	Sound Generator	Sound Generator sound/tone output pin			
SINn	USART	USART n serial data input pin			
SOTn	USART	USART n serial data output pin			
TINn	Reload Timer	Reload Timer n event input pin			
TINn_R	Reload Timer	Relocated Reload Timer n event input pin			
TOTn	Reload Timer	Reload Timer n output pin			
TOTn_R	Reload Timer	Relocated Reload Timer n output pin			
TTGn	PPG	Programmable Pulse Generator n trigger input pin			
TXn	CAN	CAN interface n TX output pin			
Vn	LCD	LCD voltage reference pin			
Vcc	Supply	Power supply pin			



Pin name	Feature	Description	
Vss	Supply	Power supply pin	
WOT	RTC	Real Time clock output pin	
WOT_R	RTC	Relocated Real Time clock output pin	
X0	Clock	Oscillator input pin	
X0A	Clock	Subclock Oscillator input pin	
X1	Clock	Oscillator output pin	
X1A	Clock	Subclock Oscillator output pin	



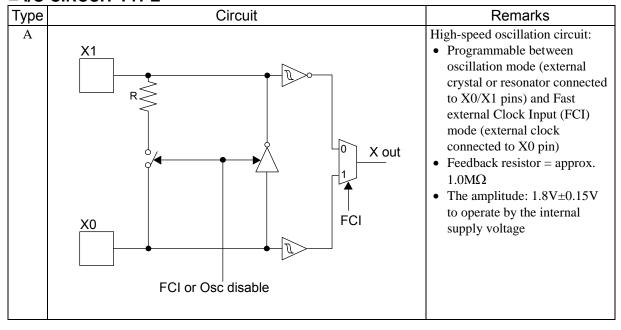
■ PIN CIRCUIT TYPE

Pin no.	I/O circuit type*	Pin name	
1	Supply	Vss	
2	F	С	
3	М	P03_7 / INT1 / SIN1	
4	Н	P13_0 / INT2 / SOT1	
5	Р	P13_1 / INT3 / SCK1 / SEG42	
6	J	P00_7 / SEG19 / SGO0	
7	J	P01_0 / SEG20 / SGA0	
8	J	P02_2 / SEG30 / CKOT0_R	
9	J	P06_3 / FRCK0 / SEG52	
10	J	P06_4 / IN0 / SEG53 / TTG0	
11	J	P06_5 / IN1 / SEG54 / TTG1	
12	J	P06_6 / TIN1 / SEG55 / IN4_R	
13	J	P06_7 / TOT1 / SEG56 / IN5_R	
14	K	P05_0 / AN8	
15	K	P05_1 / AN9	
16	Supply	AVcc	
17	G	AVRH	
18	Supply	AVss	
19	K	P05_2 / AN10	
20	K	P05_3 / AN11	
21	K	P05_4 / AN12 / INT2_R / WOT_R	
22	K	P05_5 / AN13	
23	Н	P05_6 / TIN2	
24	Н	P05_7 / TOT2	
25	R	P08_0 / PWM1P0 / AN16	
26	R	P08_1 / PWM1M0 / AN17	
27	R	P08_2 / PWM2P0 / AN18	
28	R	P08_3 / PWM2M0 / AN19	
29	Supply	DVcc	
30	Supply	DVss	
31	R	P08_4 / PWM1P1 / AN20	
32	R	P08_5 / PWM1M1 / AN21	
33	R	P08_6 / PWM2P1 / AN22	
34	R	P08_7 / PWM2M1 / AN23	
35	Н	P13_2 / PPG0 / FRCK1	
36	Н	P13_3 / PPG1 / WOT	
37	Р	P13_4 / SIN0 / INT6 / SEG45	
38	J	P13_5 / SOT0 / ADTG / INT7 / SEG46	
39	Р	P13_6 / SCK0 / CKOTX0 / SEG47	
40	Ν	P04_4 / PPG3 / SDA0	

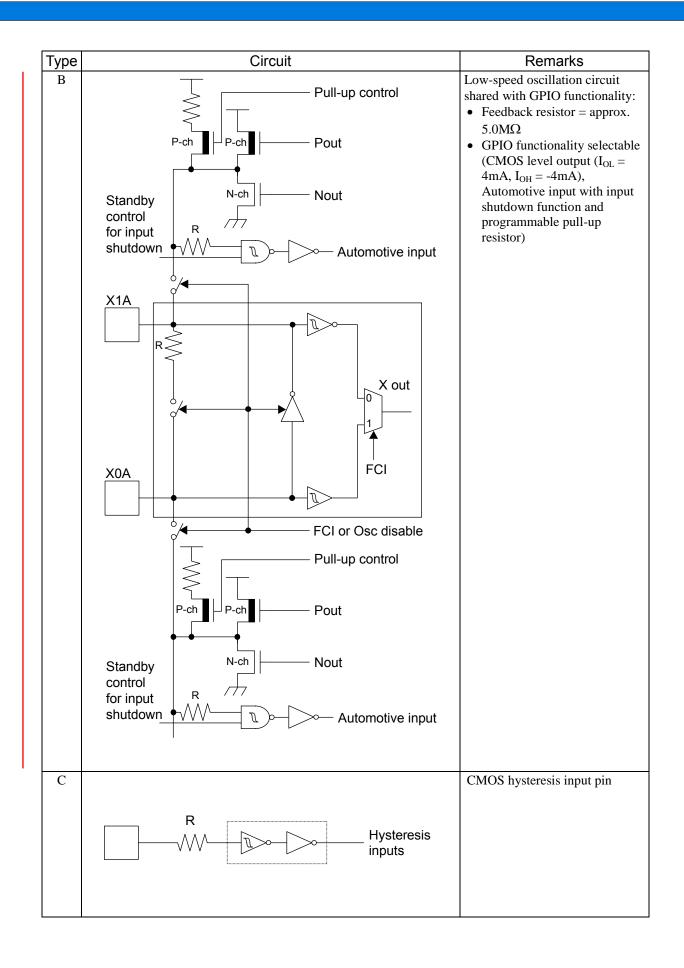
Pin no.	I/O circuit type*	Pin name		
41	N	P04_5 / SCL0		
42	Supply	Vss		
43	0	DEBUG I/F		
44	Н	P17_0		
45	С	MD		
46	A	X0		
47	A	X1		
48	Supply	Vss		
49	В	P04_0 / X0A		
50	В	P04_1 / X1A		
51	С	RSTX		
52	Н	P11_4 / PPG3_R		
53	J	P11_5 / SEG1		
54	J	P11_6 / SEG2 / FRCK0_R		
55	J	P11_7 / SEG3 / IN0_R		
56	J	P11_0 / COM0		
57	J	P11_1 / COM1 / PPG0_R		
58	J	P11_2 / COM2 / PPG1_R		
59	J	P11_3 / COM3 / PPG2_R		
60	J	P12_0 / SEG4 / IN1_R		
61	J	P12_1 / SEG5 / TIN1_R / PPG0_B		
62	J	P12_2 / SEG6 / TOT1_R / PPG1_B		
63	J	P12_3 / SEG7		
64	J	P12_4 / SEG8		
65	J	P12_5 / SEG9 / TIN2_R / PPG2_B		
66	J	P12_6 / SEG10 / TOT2_R / PPG3_B		
67	J	P12_7 / SEG11 / INT1_R		
68	J	P00_0 / SEG12 / INT3_R		
69	J	P01_1 / SEG21 / CKOT1		
70	J	P01_2 / SEG22 / CKOTX1		
71	J	P01_3 / SEG23		
72	J	P01_4 / SEG24		
73	L	P03_0 / SEG36 / V0		
74	L	P03_1 / SEG37 / V1		
75	L	P03_2 / SEG38 / V2		
76	L	P03_3 / SEG39 / V3		
77	М	P03_4 / RX0 / INT4		
78	Н	P03_5 / TX0		
79	Н	P03_6 / INT0 / NMI		
80	80 Supply Vcc			

*: See "■ I/O CIRCUIT TYPE" for details on the I/O circuit types.

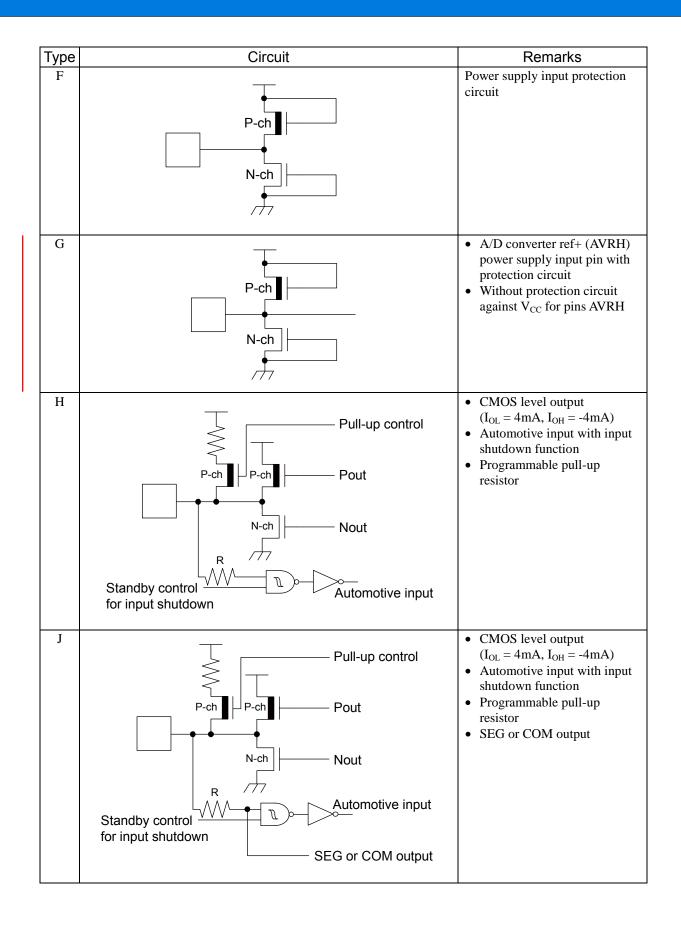
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■ I/O CIRCUIT TYPE



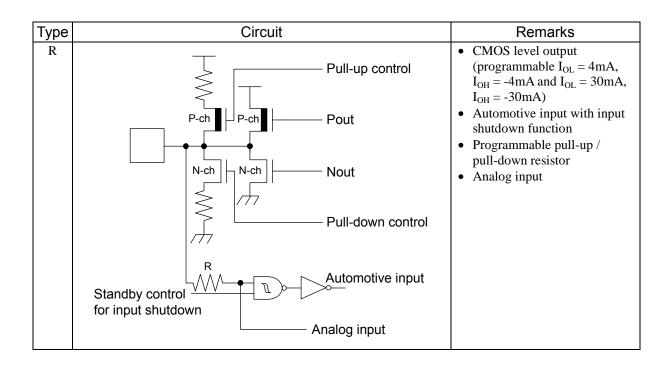
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Туре	Circuit	Remarks
K	P-ch	 CMOS level output (I_{OL} = 4mA, I_{OH} = -4mA) Automotive input with input shutdown function Programmable pull-up resistor Analog input
	Standby control	
L	P-ch Pout P-ch Pout P-ch Pout Nout R Standby control for input shutdown Vn input or SEG output	 CMOS level output (I_{OL} = 4mA, I_{OH} = -4mA) Automotive input with input shutdown function Programmable pull-up resistor Vn input or SEG output
М	P-ch P-ch Pout P-ch P-ch Pout N-ch Nout Hysteresis input Standby control for input shutdown	 CMOS level output (I_{OL} = 4mA, I_{OH} = -4mA) CMOS hysteresis input with input shutdown function Programmable pull-up resistor

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Туре	Circuit	Remarks
N	P-ch P-ch Pout P-ch P-ch Pout P-ch Nout* Hysteresis input for input shutdown	 CMOS level output (I_{OL} = 3mA, I_{OH} = -3mA) CMOS hysteresis input with input shutdown function Programmable pull-up resistor *: N-channel transistor has slew rate control according to I²C spec, irrespective of usage.
0	Standby control TTL input	 Open-drain I/O Output 25mA, Vcc = 2.7V TTL input
Р	P-ch P-ch Pout P-ch Pout P-ch Nout K Standby control for input shutdown SEG or COM output	 CMOS level output (I_{OL} = 4mA, I_{OH} = -4mA) CMOS hysteresis inputs with input shutdown function Programmable pull-up resistor SEG or COM output





MEMORY MAP

FF:FFFF _H	USER ROM*1
DE:0000 _H	
DD:FFFF _H	
	Reserved
10:0000 _H	
0F:C000 _H	Boot-ROM
0E:9000 _H	Peripheral
01:0000 _H	Reserved
	ROM/RAM
00:8000 _H	MIRROR
RAMSTART0*2	Internal RAM bank0
00:0C00 _H	Reserved
00:0380 _H	Peripheral
00:0180 _H	GPR*3
00:0100 _H	DMA
00:00F0 _H	Reserved
00:0000 _H	Peripheral

*1: For details about USER ROM area, see "■USER ROM MEMORY MAP FOR FLASH DEVICES" on the following pages.

*2: For RAMSTART addresses, see the table on the next page.

*3: Unused GPR banks can be used as RAM area.

GPR: General-Purpose Register

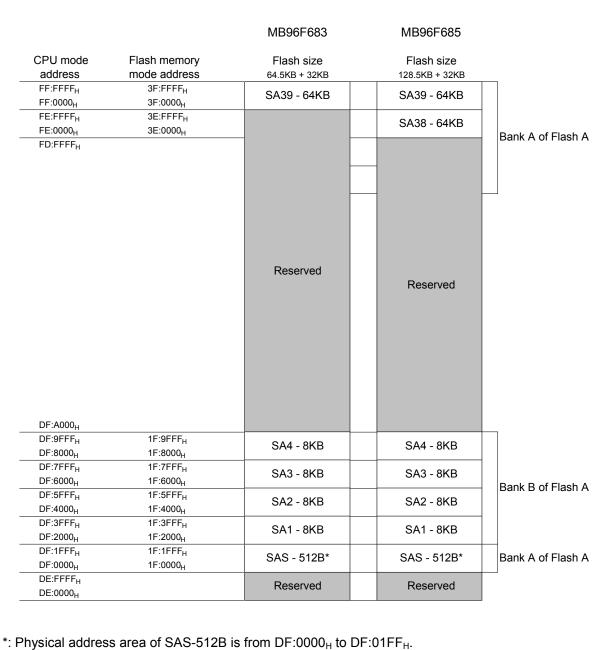
The DMA area is only available if the device contains the corresponding resource. The available RAM and ROM area depends on the device.

■ RAMSTART ADDRESSES

Devices	Bank 0 RAM size	RAMSTART0
MB96F683 MB96F685	4KB	00:7200 _H



USER ROM MEMORY MAP FOR FLASH DEVICES



Others (from DF:0200_H to DF:1FFF_H) is mirror area of SAS-512B.

Sector SAS contains the ROM configuration block RCBA at CPU address DF:0000_H -DF:01FF_H. SAS can not be used for E^2 PROM emulation.

■ SERIAL PROGRAMMING COMMUNICATION INTERFACE

USART pins for Flash serial programming (MD = 0, DEBUG I/F = 0, Serial Communication mode)

MB96680					
Pin Number	Normal Function				
37		SIN0			
38	USART0	SOT0			
39		SCK0			
3		SIN1			
4	USART1	SOT1			
5		SCK1			

■ INTERRUPT VECTOR TABLE

		IUR IABLE			
Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to	Description
0	3FC _H	CALLV0	No	program	CALLV instruction
1	3F8 _H	CALLV1	No	_	CALLV instruction
2	3F4 _H	CALLV2	No		CALLV instruction
3	3F0 _H	CALLV3	No	_	CALLV instruction
4	3EC _H	CALLV3 CALLV4	No	-	CALLV instruction
5	3E8 _H	CALLV4 CALLV5	No	-	CALLV instruction
6	3E6 _H 3E4 _H	CALLV5 CALLV6	No	-	CALLV instruction
7				-	CALLV instruction
8	3E0 _H	CALLV7 RESET	No No	-	
	3DC _H			-	Reset vector
9	3D8 _H	INT9	No	-	INT9 instruction
10	3D4 _H	EXCEPTION	No	-	Undefined instruction execution
11	3D0 _H	NMI	No	-	Non-Maskable Interrupt
12	3CC _H	DLY	No	12	Delayed Interrupt
13	3C8 _H	RC_TIMER	No	13	RC Clock Timer
14	3C4 _H	MC_TIMER	No	14	Main Clock Timer
15	3C0 _H	SC_TIMER	No	15	Sub Clock Timer
16	3BC _H	LVDI	No	16	Low Voltage Detector
17	3B8 _H	EXTINT0	Yes	17	External Interrupt 0
18	3B4 _H	EXTINT1	Yes	18	External Interrupt 1
19	3B0 _H	EXTINT2	Yes	19	External Interrupt 2
20	3AC _H	EXTINT3	Yes	20	External Interrupt 3
21	3A8 _H	EXTINT4	Yes	21	External Interrupt 4
22	3A4 _H	-	-	22	Reserved
23	3A0 _H	EXTINT6	Yes	23	External Interrupt 6
24	39C _H	EXTINT7	Yes	24	External Interrupt 7
25	398 _H	-	-	25	Reserved
26	394 _H	-	-	26	Reserved
27	390 _H	-	-	27	Reserved
28	38C _H	-	-	28	Reserved
29	388 _H	-	-	29	Reserved
30	384 _H	-	-	30	Reserved
31	380 _H	-	-	31	Reserved
32	37C _H	-	-	32	Reserved
33	378 _H	CAN0	No	33	CAN Controller 0
34	374 _H	-	-	34	Reserved
35	370 _H	-	-	35	Reserved
36	36C _H	-	-	36	Reserved
37	368 _H	_	_	37	Reserved
38	364 _H	PPG0	Yes	38	Programmable Pulse Generator 0
39	360 _H	PPG1	Yes	39	Programmable Pulse Generator 1
40	35C _H	PPG2	Yes	40	Programmable Pulse Generator 2
	JJCH	1102	105	UT	riscite i unse Generator 2

Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
41	358 _H	PPG3	Yes	41	Programmable Pulse Generator 3
42	354 _H	-	-	42	Reserved
43	350 _H	-	-	43	Reserved
44	34C _H	-	-	44	Reserved
45	348 _H	-	-	45	Reserved
46	344 _H	-	-	46	Reserved
47	340 _H	-	-	47	Reserved
48	33C _H	-	-	48	Reserved
49	338 _H	-	-	49	Reserved
50	334 _H	-	-	50	Reserved
51	330 _H	-	-	51	Reserved
52	32C _H	-	-	52	Reserved
53	328 _H	-	-	53	Reserved
54	324 _H	-	-	54	Reserved
55	320 _H	-	-	55	Reserved
56	31C _H	-	-	56	Reserved
57	318 _H	-	-	57	Reserved
58	314 _H	-	-	58	Reserved
59	310 _H	RLT1	Yes	59	Reload Timer 1
60	30C _H	RLT2	Yes	60	Reload Timer 2
61	308 _H	-	-	61	Reserved
62	304 _H	-	-	62	Reserved
63	300 _H	-	-	63	Reserved
64	2FC _H	RLT6	Yes	64	Reload Timer 6
65	$2F8_{H}$	ICU0	Yes	65	Input Capture Unit 0
66	2F4 _H	ICU1	Yes	66	Input Capture Unit 1
67	2F0 _H	-	-	67	Reserved
68	2EC _H	-	-	68	Reserved
69	2E8 _H	ICU4	Yes	69	Input Capture Unit 4
70	2E4 _H	ICU5	Yes	70	Input Capture Unit 5
71	2E0 _H	-	-	71	Reserved
72	2DC _H	-	-	72	Reserved
73	2D8 _H	-	-	73	Reserved
74	2D4 _H	-	-	74	Reserved
75	2D0 _H	-	-	75	Reserved
76	2CC _H	-	-	76	Reserved
77	2C8 _H	-	-	77	Reserved
78	2C4 _H	-	-	78	Reserved
79	2C0 _H	-	-	79	Reserved
80	2BC _H	-	-	80	Reserved

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Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description	
81	2B8 _H	-	-	81	Reserved	
82	2B4 _H	-	-	82	Reserved	
83	2B0 _H	-	-	83	Reserved	
84	2AC _H	-	-	84	Reserved	
85	2A8 _H	-	-	85	Reserved	
86	2A4 _H	-	-	86	Reserved	
87	2A0 _H	-	-	87	Reserved	
88	29C _H	-	-	88	Reserved	
89	298 _H	FRT0	Yes	89	Free-Running Timer 0	
90	294 _H	FRT1	Yes	90	Free-Running Timer 1	
91	290 _H	-	-	91	Reserved	
92	28C _H	-	-	92	Reserved	
93	288 _H	RTC0	No	93	Real Time Clock	
94	284 _H	CAL0	No	94	Clock Calibration Unit	
95	280 _H	SG0	No	95	Sound Generator 0	
96	27C _H	IIC0	Yes	96	I ² C interface 0	
97	278 _H	-	-	97	Reserved	
98	274 _H	ADC0	Yes	98	A/D Converter 0	
99	270 _H	-	-	99	Reserved	
100	26C _H	-	-	100	Reserved	
101	268 _H	LINR0	Yes	101	LIN USART 0 RX	
102	264 _H	LINT0	Yes	102	LIN USART 0 TX	
103	260 _H	LINR1	Yes	103	LIN USART 1 RX	
104	25C _H	LINT1	Yes	104	LIN USART 1 TX	
105	258 _H	-	-	105	Reserved	
106	254 _H	-	-	106	Reserved	
107	250 _H	-	-	107	Reserved	
108	24C _H	-	-	108	Reserved	
109	248 _H	-	-	109	Reserved	
110	244 _H	-	-	110	Reserved	
111	240 _H	-	-	111	Reserved	
112	23C _H	-	-	112	Reserved	
113	238 _H	-	-	113	Reserved	
114	234 _H	-	-	114	Reserved	
115	230 _H	-	-	115	Reserved	
116	22C _H	-	-	116	Reserved	
117	228 _H	-	-	117	Reserved	
118	224 _H	-	-	118	Reserved	
119	220 _H	-	-	119	Reserved	
120	21C _H	-	-	120	Reserved	

Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description	
121	218 _H	-	-	121	Reserved	
122	214 _H	-	-	122	Reserved	
123	210 _H	-	-	123	Reserved	
124	20C _H	-	-	124	Reserved	
125	208 _H	-	-	125	Reserved	
126	204 _H	-	-	126	Reserved	
127	200 _H	-	-	127	Reserved	
128	1FC _H	-	-	128	Reserved	
129	1F8 _H	-	-	129	Reserved	
130	1F4 _H	-	-	130	Reserved	
131	1F0 _H	-	-	131	Reserved	
132	1EC _H	-	-	132	Reserved	
133	1E8 _H	FLASHA	Yes	133	Flash memory A interrupt	
134	1E4 _H	-	-	134	Reserved	
135	1E0 _H	-	-	135	Reserved	
136	1DC _H	-	-	136	Reserved	
137	1D8 _H	-	-	137	Reserved	
138	1D4 _H	-	-	138	Reserved	
139	1D0 _H	ADCRC0	No	139	A/D Converter 0 - Range Comparator	
140	1CC _H	ADCPD0	No	140	A/D Converter 0 - Pulse detection	
141	1C8 _H	-	-	141	Reserved	
142	1C4 _H	-	-	142	Reserved	
143	1C0 _H	-	-	143	Reserved	

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HANDLING PRECAUTIONS

Any semiconductor devices have inherently a certain rate of failure. The possibility of failure is greatly affected by the conditions in which they are used (circuit conditions, environmental conditions, etc.). This page describes precautions that must be observed to minimize the chance of failure and to obtain higher reliability from your FUJITSU SEMICONDUCTOR semiconductor devices.

1. Precautions for Product Design

This section describes precautions when designing electronic equipment using semiconductor devices.

Absolute Maximum Ratings

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of certain established limits, called absolute maximum ratings. Do not exceed these ratings.

Recommended Operating Conditions

Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their sales representative beforehand.

Processing and Protection of Pins

These precautions must be followed when handling the pins which connect semiconductor devices to power supply and input/output functions.

(1) Preventing Over-Voltage and Over-Current Conditions

Exposure to voltage or current levels in excess of maximum ratings at any pin is likely to cause deterioration within the device, and in extreme cases leads to permanent damage of the device. Try to prevent such overvoltage or over-current conditions at the design stage.

(2) Protection of Output Pins

Shorting of output pins to supply pins or other output pins, or connection to large capacitance can cause large current flows. Such conditions if present for extended periods of time can damage the device.

Therefore, avoid this type of connection.

(3) Handling of Unused Input Pins

Unconnected input pins with very high impedance levels can adversely affect stability of operation. Such pins should be connected through an appropriate resistance to a power supply pin or ground pin.

· Latch-up

Semiconductor devices are constructed by the formation of P-type and N-type areas on a substrate. When subjected to abnormally high voltages, internal parasitic PNPN junctions (called thyristor structures) may be formed, causing large current levels in excess of several hundred mA to flow continuously at the power supply pin. This condition is called latch-up.

CAUTION: The occurrence of latch-up not only causes loss of reliability in the semiconductor device, but can cause injury or damage from high heat, smoke or flame. To prevent this from happening, do the following:

- (1) Be sure that voltages applied to pins do not exceed the absolute maximum ratings. This should include attention to abnormal noise, surge levels, etc.
- (2) Be sure that abnormal current flows do not occur during the power-on sequence.

· Observance of Safety Regulations and Standards

Most countries in the world have established standards and regulations regarding safety, protection from electromagnetic interference, etc. Customers are requested to observe applicable regulations and standards in the design of products.

Fail-Safe Design

Any semiconductor devices have inherently a certain rate of failure. You must protect against injury, damage or loss from such failures by incorporating safety design measures into your facility and equipment such as redundancy, fire protection, and prevention of over-current levels and other abnormal operating conditions.

· Precautions Related to Usage of Devices

FUJITSU SEMICONDUCTOR semiconductor devices are intended for use in standard applications (computers, office automation and other office equipment, industrial, communications, and measurement equipment, personal or household devices, etc.).

CAUTION: Customers considering the use of our products in special applications where failure or abnormal operation may directly affect human lives or cause physical injury or property damage, or where extremely high levels of reliability are demanded (such as aerospace systems, atomic energy controls, sea floor repeaters, vehicle operating controls, medical devices for life support, etc.) are requested to consult with sales representatives before such use. The company will not be responsible for damages arising from such use without prior approval.

2. Precautions for Package Mounting

Package mounting may be either lead insertion type or surface mount type. In either case, for heat resistance during soldering, you should only mount under FUJITSU SEMICONDUCTOR's recommended conditions. For detailed information about mount conditions, contact your sales representative.

Lead Insertion Type

Mounting of lead insertion type packages onto printed circuit boards may be done by two methods: direct soldering on the board, or mounting by using a socket.

Direct mounting onto boards normally involves processes for inserting leads into through-holes on the board and using the flow soldering (wave soldering) method of applying liquid solder. In this case, the soldering process usually causes leads to be subjected to thermal stress in excess of the absolute ratings for storage temperature. Mounting processes should conform to FUJITSU SEMICONDUCTOR recommended mounting conditions.

If socket mounting is used, differences in surface treatment of the socket contacts and IC lead surfaces can lead to contact deterioration after long periods. For this reason it is recommended that the surface treatment of socket contacts and IC leads be verified before mounting.

Surface Mount Type

Surface mount packaging has longer and thinner leads than lead-insertion packaging, and therefore leads are more easily deformed or bent. The use of packages with higher pin counts and narrower pin pitch results in increased susceptibility to open connections caused by deformed pins, or shorting due to solder bridges.

You must use appropriate mounting techniques. FUJITSU SEMICONDUCTOR recommends the solder reflow method, and has established a ranking of mounting conditions for each product. Users are advised to mount packages in accordance with FUJITSU SEMICONDUCTOR ranking of recommended conditions.

· Lead-Free Packaging

CAUTION: When ball grid array (BGA) packages with Sn-Ag-Cu balls are mounted using Sn-Pb eutectic soldering, junction strength may be reduced under some conditions of use.

Storage of Semiconductor Devices

Because plastic chip packages are formed from plastic resins, exposure to natural environmental conditions will cause absorption of moisture. During mounting, the application of heat to a package that has absorbed moisture can cause surfaces to peel, reducing moisture resistance and causing packages to crack. To prevent, do the following:

- (1) Avoid exposure to rapid temperature changes, which cause moisture to condense inside the product. Store products in locations where temperature changes are slight.
- (2) Use dry boxes for product storage. Products should be stored below 70% relative humidity, and at temperatures between 5°C and 30°C.
 When you open Dry Package that recommends humidity 40% to 70% relative humidity.
- (3) When necessary, FUJITSU SEMICONDUCTOR packages semiconductor devices in highly moisture-resistant aluminum laminate bags, with a silica gel desiccant. Devices should be sealed in their aluminum laminate bags for storage.
- (4) Avoid storing packages where they are exposed to corrosive gases or high levels of dust.

Baking

Packages that have absorbed moisture may be de-moisturized by baking (heat drying). Follow the FUJITSU SEMICONDUCTOR recommended conditions for baking.

Condition: 125°C/24 h

Static Electricity

Because semiconductor devices are particularly susceptible to damage by static electricity, you must take the following precautions:

- (1) Maintain relative humidity in the working environment between 40% and 70%. Use of an apparatus for ion generation may be needed to remove electricity.
- (2) Electrically ground all conveyors, solder vessels, soldering irons and peripheral equipment.
- (3) Eliminate static body electricity by the use of rings or bracelets connected to ground through high resistance (on the level of 1 MΩ). Wearing of conductive clothing and shoes, use of conductive floor mats and other measures to minimize shock loads is recommended.
- (4) Ground all fixtures and instruments, or protect with anti-static measures.
- (5) Avoid the use of styrofoam or other highly static-prone materials for storage of completed board assemblies.

3. Precautions for Use Environment

Reliability of semiconductor devices depends on ambient temperature and other conditions as described above.

For reliable performance, do the following:

(1) Humidity

Prolonged use in high humidity can lead to leakage in devices as well as printed circuit boards. If high humidity levels are anticipated, consider anti-humidity processing.

- (2) Discharge of Static Electricity When high-voltage charges exist close to semiconductor devices, discharges can cause abnormal operation. In such cases, use anti-static measures or processing to prevent discharges.
- (3) Corrosive Gases, Dust, or Oil

Exposure to corrosive gases or contact with dust or oil may lead to chemical reactions that will adversely affect the device. If you use devices in such conditions, consider ways to prevent such exposure or to protect the devices.

(4) Radiation, Including Cosmic Radiation

Most devices are not designed for environments involving exposure to radiation or cosmic radiation. Users should provide shielding as appropriate.

(5) Smoke, Flame

CAUTION: Plastic molded devices are flammable, and therefore should not be used near combustible substances. If devices begin to smoke or burn, there is danger of the release of toxic gases. Customers considering the use of FUJITSU SEMICONDUCTOR products in other special environmental conditions should consult with sales representatives.

Please check the latest handling precautions at the following URL. http://edevice.fujitsu.com/fj/handling-e.pdf

HANDLING DEVICES

Special care is required for the following when handling the device:

- Latch-up prevention
- Unused pins handling
- External clock usage
- Notes on PLL clock mode operation
- Power supply pins (Vcc/Vss)
- Crystal oscillator and ceramic resonator circuit
- Turn on sequence of power supply to A/D converter and analog inputs
- Pin handling when not using the A/D converter
- Notes on Power-on
- Stabilization of power supply voltage
- SMC power supply pins
- Serial communication
- Mode Pin (MD)

1. Latch-up prevention

CMOS IC chips may suffer latch-up under the following conditions:

- A voltage higher than V_{CC} or lower than V_{SS} is applied to an input or output pin.
- A voltage higher than the rated voltage is applied between Vcc pins and Vss pins.
- The AV_{CC} power supply is applied before the V_{CC} voltage.

Latch-up may increase the power supply current dramatically, causing thermal damages to the device.

For the same reason, extra care is required to not let the analog power-supply voltage (AV_{CC} , AVRH) exceed the digital power-supply voltage.

2. Unused pins handling

Unused input pins can be left open when the input is disabled (corresponding bit of Port Input Enable register PIER = 0).

Leaving unused input pins open when the input is enabled may result in misbehavior and possible permanent damage of the device. To prevent latch-up, they must therefore be pulled up or pulled down through resistors which should be more than $2k\Omega$.

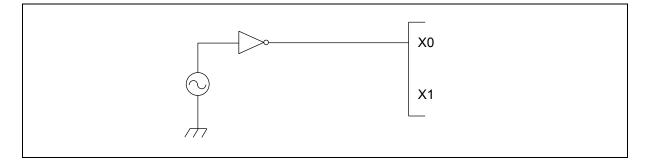
Unused bidirectional pins can be set either to the output state and be then left open, or to the input state with either input disabled or external pull-up/pull-down resistor as described above.

3. External clock usage

The permitted frequency range of an external clock depends on the oscillator type and configuration. See AC Characteristics for detailed modes and frequency limits. Single and opposite phase external clocks must be connected as follows:

(1) Single phase external clock for Main oscillator

When using a single phase external clock for the Main oscillator, X0 pin must be driven and X1 pin left open. And supply 1.8V power to the external clock.

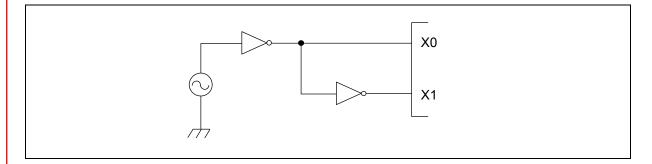


(2) Single phase external clock for Sub oscillator

When using a single phase external clock for the Sub oscillator, "External clock mode" must be selected and X0A/P04_0 pin must be driven. X1A/P04_1 pin can be configured as GPIO.

(3) Opposite phase external clock

When using an opposite phase external clock, X1 (X1A) pins must be supplied with a clock signal which has the opposite phase to the X0 (X0A) pins. Supply level on X0 and X1 pins must be 1.8V.



4. Notes on PLL clock mode operation

If the microcontroller is operated with PLL clock mode and no external oscillator is operating or no external clock is supplied, the microcontroller attempts to work with the free oscillating PLL. Performance of this operation, however, cannot be guaranteed.

5. Power supply pins (Vcc/Vss)

It is required that all V_{CC} -level as well as all V_{SS} -level power supply pins are at the same potential. If there is more than one V_{CC} or V_{SS} level, the device may operate incorrectly or be damaged even within the guaranteed operating range.

Vcc and Vss pins must be connected to the device from the power supply with lowest possible impedance. The smoothing capacitor at Vcc pin must use the one of a capacity value that is larger than Cs.

Besides this, as a measure against power supply noise, it is required to connect a bypass capacitor of about 0.1μ F between Vcc and Vss pins as close as possible to Vcc and Vss pins.

6. Crystal oscillator and ceramic resonator circuit

Noise at X0, X1 pins or X0A, X1A pins might cause abnormal operation. It is required to provide bypass capacitors with shortest possible distance to X0, X1 pins and X0A, X1A pins, crystal oscillator (or ceramic resonator) and ground lines, and, to the utmost effort, that the lines of oscillation circuit do not cross the lines of other circuits.

It is highly recommended to provide a printed circuit board art work surrounding X0, X1 pins and X0A, X1A pins with a ground area for stabilizing the operation.

It is highly recommended to evaluate the quartz/MCU or resonator/MCU system at the quartz or resonator manufacturer, especially when using low-Q resonators at higher frequencies.

7. Turn on sequence of power supply to A/D converter and analog inputs

It is required to turn the A/D converter power supply (AV_{CC}, AVRH) and analog inputs (ANn) on after turning the digital power supply (V_{CC}) on.

It is also required to turn the digital power off after turning the A/D converter supply and analog inputs off. In this case, AVRH must not exceed AV_{CC} . Input voltage for ports shared with analog input ports also must not exceed AV_{CC} (turning the analog and digital power supplies simultaneously on or off is acceptable).

8. Pin handling when not using the A/D converter

If the A/D converter is not used, the power supply pins for A/D converter should be connected such as $AV_{CC} = V_{CC}$, $AV_{SS} = AVRH = V_{SS}$.



9. Notes on Power-on

To prevent malfunction of the internal voltage regulator, supply voltage profile while turning the power supply on should be slower than 50µs from 0.2V to 2.7V.

10. Stabilization of power supply voltage

If the power supply voltage varies acutely even within the operation safety range of the V_{CC} power supply voltage, a malfunction may occur. The V_{CC} power supply voltage must therefore be stabilized. As stabilization guidelines, the power supply voltage must be stabilized in such a way that V_{CC} ripple fluctuations (peak to peak value) in the commercial frequencies (50Hz to 60Hz) fall within 10% of the standard V_{CC} power supply voltage and the transient fluctuation rate becomes $0.1V/\mu s$ or less in instantaneous fluctuation for power supply switching.

11. SMC power supply pins

All DVcc /DVss pins must be set to the same level as the Vcc /Vss pins. Note that the SMC I/O pin state is undefined if DV_{CC} is powered on and V_{CC} is below 3V. To avoid this, V_{CC} must always be powered on before DV_{CC} .

DVcc/DVss must be applied when using SMC I/O pin as GPIO.

12. Serial communication

There is a possibility to receive wrong data due to noise or other causes on the serial communication. Therefore, design a printed circuit board so as to avoid noise.

Consider receiving of wrong data when designing the system. For example apply a checksum and retransmit the data if an error occurs.

13. Mode Pin (MD)

Connect the mode pin directly to Vcc or Vss pin. To prevent the device unintentionally entering test mode due to noise, lay out the printed circuit board so as to minimize the distance from the mode pin to Vcc or Vss pin and provide a low-impedance connection.

■ ELECTRICAL CHARACTERISTICS

1. Absolute Maximum Ratings

Parameter	Symbol	Condition	Rating		Unit	Remarks
T arameter	Cymbol	Condition	Min	Max	Unit	I CILIAINS
Power supply voltage* ¹	V _{CC}	-	V _{SS} - 0.3	$V_{SS} + 6.0$	v	
Analog power supply voltage ^{*1}	AV _{CC}	-	V _{SS} - 0.3	$V_{SS} + 6.0$	V	$V_{CC} = AV_{CC}^{*2}$
Analog reference voltage ^{*1}	AVRH	-	V _{SS} - 0.3	$V_{SS} + 6.0$	V	$AV_{CC} \ge AVRH,$ $AVRH \ge AV_{SS}$
SMC Power supply ^{*1}	DV _{CC}	-	V _{SS} - 0.3	$V_{SS} + 6.0$	V	$V_{CC} = AV_{CC} = DV_{CC}^{*2}$
LCD power supply voltage*1	V0 to V3	-	V _{SS} - 0.3	$V_{SS} + 6.0$	V	V0 to V3 must not exceed V _{CC}
Input voltage*1	VI	-	V _{SS} - 0.3	$V_{SS} + 6.0$	V	$V_{I} \leq (D)V_{CC} + 0.3V^{*3}$
Output voltage*1	Vo	-	V _{SS} - 0.3	$V_{SS} + 6.0$	V	$V_0 \le (D)V_{CC} + 0.3V^{*3}$
Maximum Clamp Current	I _{CLAMP}	-	-4.0	+4.0	mA	Applicable to general purpose I/O pins * ⁴
Total Maximum Clamp Current	$\Sigma I_{CLAMP} $	-	-	21	mA	Applicable to general purpose I/O pins * ⁴
	I _{OL}	-	-	15	mA	Normal port
"L" level maximum		$T_A = -40^{\circ}C$	-	52	mA	
	т	$T_A = +25^{\circ}C$	-	39	mA	II: als assume a surf
output current	I _{OLSMC}	$T_A = +85^{\circ}C$	-	32	mA	High current port
		$T_{A} = +105^{\circ}C$	-	30	mA	
	I _{OLAV}	-	-	4	mA	Normal port
		$T_A = -40^{\circ}C$	-	40	mA	High current port
"L" level average	I _{OLAVSMC}	$T_A = +25^{\circ}C$	-	30	mA	
output current		$T_A = +85^{\circ}C$	_	25	mA	
		$T_A = +105^{\circ}C$	-	23	mA	
"L" level maximum	ΣI_{OL}	-	-	46	mA	Normal port
overall output current	ΣI _{OLSMC}	-	-	180	mA	High current port
"L" level average overall output	ΣI_{OLAV}	-	-	23	mA	Normal port
current	$\Sigma I_{OLAVSMC}$	-	-	90	mA	High current port
	I _{OH}	-	-	-15	mA	Normal port
	imum	$T_A = -40^{\circ}C$	-	-52	mA	High current port
"H" level maximum		$T_A = +25^{\circ}C$	-	-39	mA	
output current		$T_A = +85^{\circ}C$	-	-32	mA	
		$T_{A} = +105^{\circ}C$	-	-30	mA	
	I _{OHAV}	-	-	-4	mA	Normal port
	erage	$T_A = -40^{\circ}C$	-	-40	mA	
"H" level average		$T_A = +25^{\circ}C$	-	-30	mA	
output current		$T_{A} = +25^{\circ}C$ $T_{A} = +85^{\circ}C$	-	-25	mA	High current port
		$T_{A} = +105^{\circ}C$	-	-23	mA	
"H" level maximum	ΣI _{OH}	-	-	-46	mA	Normal port
overall output current	ΣI _{OHSMC}	-	-	-180	mA	High current port
"H" level average	ΣI_{OHAV}	-	-	-23	mA	Normal port
overall output current	$\Sigma I_{OHAVSMC}$	-	-	-90	mA	High current port



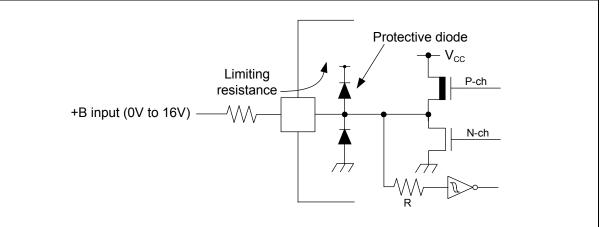
Deremeter	Symbol	Condition	Rating		Linit	Remarks
Parameter			Min	Max	Unit	Remarks
Power consumption* ⁵	P _D	T_{A} = +105°C	-	317 ^{*6}	mW	
Operating ambient temperature	T_A	-	-40	+105	°C	
Storage temperature	T _{STG}	-	-55	+150	°C	

*1: This parameter is based on $V_{SS} = AV_{SS} = DV_{SS} = 0V$.

*2: AV_{CC} and V_{CC} and DV_{CC} must be set to the same voltage. It is required that AV_{CC} does not exceed V_{CC} , DV_{CC} and that the voltage at the analog inputs does not exceed AV_{CC} when the power is switched on.

- *3: V_I and V_O should not exceed V_{CC} + 0.3V. V_I should also not exceed the specified ratings. However if the maximum current to/from an input is limited by some means with external components, the I_{CLAMP} rating supersedes the V_I rating. Input/Output voltages of high current ports depend on DV_{CC}. Input/Output voltages of standard ports depend on V_{CC}.
- *4: Applicable to all general purpose I/O pins (Pnn_m).
 - Use within recommended operating conditions.
 - Use at DC voltage (current).
 - The +B signal should always be applied a limiting resistance placed between the +B signal and the microcontroller.
 - The value of the limiting resistance should be set so that when the +B signal is applied the input current to the microcontroller pin does not exceed rated values, either instantaneously or for prolonged periods.
 - Note that when the microcontroller drive current is low, such as in the power saving modes, the +B input potential may pass through the protective diode and increase the potential at the V_{CC} pin, and this may affect other devices.
 - Note that if a +B signal is input when the microcontroller power supply is off (not fixed at 0V), the power supply is provided from the pins, so that incomplete operation may result.
 - Note that if the +B input is applied during power-on, the power supply is provided from the pins and the resulting supply voltage may not be sufficient to operate the Power reset.
 - The DEBUG I/F pin has only a protective diode against V_{SS}. Hence it is only permitted to input a negative clamping current (4mA). For protection against positive input voltages, use an external clamping diode which limits the input voltage to maximum 6.0V.

• Sample recommended circuits:



*5: The maximum permitted power dissipation depends on the ambient temperature, the air flow velocity and the thermal conductance of the package on the PCB.

The actual power dissipation depends on the customer application and can be calculated as follows: $P_D = P_{IO} + P_{INT}$

 $P_{IO} = \Sigma (V_{OL} \times I_{OL} + V_{OH} \times I_{OH})$ (I/O load power dissipation, sum is performed on all I/O ports)

 $P_{INT} = V_{CC} \times (I_{CC} + I_A)$ (internal power dissipation)

 I_{CC} is the total core current consumption into V_{CC} as described in the "DC characteristics" and depends on the selected operation mode and clock frequency and the usage of functions like Flash programming. I_A is the analog current consumption into AV_{CC} .

*6: Worst case value for a package mounted on single layer PCB at specified T_A without air flow.

<WARNING>

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

	•	0				$(V_{SS} = AV_{SS} = DV_{SS} = 0V)$
Parameter	Symbol		Value		Unit	Remarks
Falametei	Symbol	Min	Тур	Max	Onit	Remarks
Power supply	V _{CC} ,	2.7	-	5.5	V	
voltage	AV _{CC} , DV _{CC}	2.0	-	5.5	v	Maintains RAM data in stop mode
Smoothing capacitor at C pin	Cs	0.5	1.0 to 3.9	4.7	μF	$ 1.0\mu F \text{ (Allowance within } \pm 50\% \text{)} \\ 3.9\mu F \text{ (Allowance within } \pm 20\% \text{)} \\ Please use the ceramic capacitor or the capacitor of the frequency response of this level. \\ The smoothing capacitor at V_{CC} must use the one of a capacity value that is larger than C_S. $

2. Recommended Operating Conditions

<WARNING>

The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating condition ranges. Operation outside these ranges may adversely affect reliability and could result in device failure. No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their representatives beforehand.

3. DC Characteristics

(1) Current Rating

	-	$V_{\rm CC} = A^{\prime}$	$V_{\rm CC} = DV_{\rm CC} = 2.7$ V to 5.5V, V _S	$s_{s} = AV$	$s_{ss} = DV_s$	s = 0V, T	$A = -40^{\circ}$	$^{\circ}C$ to + 105 $^{\circ}C$)																																	
Parameter	Symbol	Pin name	Conditions	Min	Value	r	Unit	Remarks																																	
		name	PLL Run mode with CLKS1/2 = CLKB = CLKP1/2 = 32MHz	-	<u>Тур</u> 25	Max -	mA	$T_A = +25^{\circ}C$																																	
	I _{CCPLL}		Flash 0 wait (CLKRC and CLKSC stopped)	-	_	34	mA	$T_{A} = +105^{\circ}C$																																	
	I _{CCMAIN}		Main Run mode with CLKS1/2 = CLKB = CLKP1/2 = 4MHz	-	3.5	-	mA	$T_A = +25^{\circ}C$																																	
	-CCMAIN		Flash 0 wait (CLKPLL, CLKSC and CLKRC stopped)	-	-	7.5	mA	$T_A = +105^{\circ}C$																																	
Power supply	I _{CCRCH}	Vcc	RC Run mode with CLKS1/2 = CLKB = CLKP1/2 = CLKRC = 2MHz	-	1.7	-	mA	$T_A = +25^{\circ}C$																																	
current in Run modes ^{*1}			Flash 0 wait (CLKMC, CLKPLL and CLKSC stopped)	-	-	5.5	mA	$T_A = +105^{\circ}C$																																	
	T										RC Run mode with CLKS1/2 = CLKB = CLKP1/2 = CLKRC = 100kHz	-	0.15	-	mA	$T_A = +25^{\circ}C$																									
	I _{CCRCL}		Flash 0 wait (CLKMC, CLKPLL and CLKSC stopped)	-	-	3.2	mA	$T_A = +105^{\circ}C$																																	
	T												-	-	-														-	-	-	-	-	-	-	Sub Run mode with CLKS1/2 = CLKB = CLKP1/2 = 32kHz	-	0.1	-	mA	$T_A = +25^{\circ}C$
	I _{CCSUB}		Flash 0 wait (CLKMC, CLKPLL and CLKRC stopped)	-	-	3	mA	$T_{\rm A}=+105^{\circ}C$																																	

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Parameter	Symbol	Pin	Conditions		Value		Unit	Remarks
Parameter	Symbol	name	Conditions	Min	Тур	Max	Unit	Remarks
	I _{CCSPLL}		PLL Sleep mode with CLKS1/2 = CLKP1/2 = 32MHz	-	6.5	-	mA	$T_A = +25^{\circ}C$
	CCSTEL		(CLKRC and CLKSC stopped)	-	-	13	mA	$T_{\rm A}=+105^{\circ}C$
	T		Main Sleep mode with CLKS1/2 = CLKP1/2 = 4MHz,	-	0.9	-	mA	$T_A = +25^{\circ}C$
	I _{CCSMAIN}		SMCR:LPMSS = 0 (CLKPLL, CLKRC and CLKSC stopped)	-	-	4	mA	$T_A = +105^{\circ}C$
Power supply current in	I _{CCSRCH}	Vcc	RC Sleep mode with CLKS1/2 = CLKP1/2 = CLKRC = 2MHz, SMCR:LPMSS = 0 (CLKMC, CLKPLL and CLKSC stopped)	-	0.5	-	mA	$T_A = +25^{\circ}C$
Sleep modes ^{*1}				-	-	3.5	mA	$T_A = +105^{\circ}C$
	I _{CCSRCL}		RC Sleep mode with CLKS1/2 = CLKP1/2 = CLKRC = 100kHz	-	0.06	-	mA	$T_A = +25^{\circ}C$
	COMPL		(CLKMC, CLKPLL and CLKSC stopped)	-	-	2.7	mA	$T_{\rm A}=+105^{\circ}C$
			Sub Sleep mode with CLKS1/2 = CLKP1/2 =	-	0.04	-	mA	$T_A = +25^{\circ}C$
	I _{CCSSUB}		32kHz, (CLKMC, CLKPLL and CLKRC stopped)	-	-	2.5	mA	$T_A = +105^{\circ}C$

Parameter	Symbol	Pin	Conditions		Value		Unit	Remarks
Falametei	Symbol	name	Conditions	Min	Тур	Max	Onit	Remarks
	т		PLL Timer mode with	-	1880	2245	μΑ	$T_A = +25^{\circ}C$
	I _{CCTPLL}		CLKPLL = 32MHz (CLKRC and CLKSC stopped)	-	-	3140	μΑ	$T_A = +105^{\circ}C$
	т		Main Timer mode with CLKMC = 4MHz, SMCR:LPMSS = 0	-	285	325	μΑ	$T_A = +25^{\circ}C$
	I _{CCTMAIN}		CLKPLL, CLKRC and CLKSC stopped)	-	-	1055	μΑ	$T_A = +105^{\circ}C$
Power supply current in	I _{CCTRCH}	Vcc	RC Timer mode with CLKRC = 2MHz, SMCR:LPMSS = 0	-	160	210	μΑ	$T_A = +25^{\circ}C$
Timer modes ^{*2}	1CCTRCH		(CLKPLL, CLKMC and CLKSC stopped)	-	-	970	μΑ	$T_A = +105^{\circ}C$
	T		RC Timer mode with CLKRC = 100kHz	-	30	70	μΑ	$T_A = +25^{\circ}C$
	I _{CCTRCL}		(CLKPLL, CLKMC and CLKSC stopped)	-	-	820	μΑ	$T_A=+105^{\circ}C$
	I		Sub Timer mode with CLKSC = 32kHz	-	25	55	μΑ	$T_A = +25^{\circ}C$
	I _{CCTSUB}		(CLKMC, CLKPLL and CLKRC stopped)	-	-	800	μΑ	$T_A = +105^{\circ}C$

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Parameter	Symbol	Pin	Conditions		Value		Unit	Remarks
Farameter	Symbol	name	e Conditions Min		Тур	Max	Unit	Remarks
Power supply current in Stop	I _{CCH}	Vcc	-	-	20	55	μΑ	$T_A = +25^{\circ}C$
mode ^{*3}				-	-	800	μΑ	$T_A=+105^\circ C$
Flash Power Down current	I _{CCFLASHPD}	Vcc	-	-	36	70	μΑ	
Power supply current	T	Vcc	Low voltage	-	5	-	μΑ	$T_A = +25^{\circ}C$
for active Low Voltage detector ^{*4}	I _{CCLVD}		detector enabled	-	-	12.5	μΑ	$T_A = +105^{\circ}C$
Flash Write/	T	N/		-	12.5	-	mA	$T_A = +25^{\circ}C$
Erase current* ⁵	I _{CCFLASH}	Vcc	-	-	-	20	mA	$T_{A}=+105^{\circ}C$

*1: The power supply current is measured with a 4MHz external clock connected to the Main oscillator and a 32kHz external clock connected to the Sub oscillator. See chapter "Standby mode and voltage regulator control circuit" of the Hardware Manual for further details about voltage regulator control. Current for "On Chip Debugger" part is not included. Power supply current in Run mode does not include Flash Write / Erase current.

*2: The power supply current in Timer mode is the value when Flash is in Power-down / reset mode. When Flash is not in Power-down / reset mode, I_{CCFLASHPD} must be added to the Power supply current. The power supply current is measured with a 4MHz external clock connected to the Main oscillator and a 32kHz external clock connected to the Sub oscillator. The current for "On Chip Debugger" part is not included.

*3: The power supply current in Stop mode is the value when Flash is in Power-down / reset mode. When Flash is not in Power-down / reset mode, I_{CCFLASHPD} must be added to the Power supply current.

*4: When low voltage detector is enabled, I_{CCLVD} must be added to Power supply current.

*5: When Flash Write / Erase program is executed, $I_{CCFLASH}$ must be added to Power supply current.

(2) Pin Characteristics

r			$V_{\rm CC} = DV_{\rm CC} = 2.7V$ to 5.5V				V, T_A	$= -40^{\circ}C \text{ to} + 105^{\circ}C)$	
Parameter	Symbol	Pin	Conditions		Value		Unit	Remarks	
rarameter	Symbol	name	Conditions	Min	Тур	Max	Onit	I CILIAL KS	
				V _{CC}		V _{CC}	v	CMOS Hysteresis	
"H" level input voltage	N/	Port inputs	-	$\times 0.7$	-	+0.3	v	input	
	V _{IH}	Pnn_m		V _{CC}		V _{CC}	v	AUTOMOTIVE	
			-	$\times 0.8$	-	+0.3	v	Hysteresis input	
	V	VO	External clock in	VD		VD	v	$MD_{1.0}M_{1.0}$ 15 $M_{1.0}$	
"TT" 11	V _{IHX0S}	X0	"Fast Clock Input mode"	$\times 0.8$	-	VD	v	VD=1.8V±0.15V	
	V	VOA	External clock in	V _{CC}		V _{CC}	v		
-	V _{IHX0AS}	X0A	"Oscillation mode"	$\times 0.8$	-	+0.3	v		
voltage	V	RSTX		V _{CC}		V _{CC}	v	CMOS Hysteresis	
	V _{IHR}	KSIA	-	$\times 0.8$	-	+ 0.3	v	input	
	V	MD		V _{CC}		V _{CC}	v	CMOS Hysteresis	
	V _{IHM}	MD	-	- 0.3	-	+ 0.3	v	input	
	V _{IHD}	DEBUG		2.0		V _{CC}	v	TTL Input	
	♥ IHD	I/F	-	2.0	-	+ 0.3	v	-	
		Port		V _{SS}		V_{CC}	v	CMOS Hysteresis	
	V _{IL}	inputs		- 0.3	-	× 0.3	v	input	
	▼ IL	Pnn_m		V _{SS}		V_{CC}	v	AUTOMOTIVE	
		1 mi_m		- 0.3	-	$\times 0.5$	v	Hysteresis input	
	V _{ILX0S}	X0	External clock in "Fast	V _{ss}		VD	v	VD=1.8V±0.15V	
"L" level	V ILX0S	Л	Clock Input mode"	▼ SS	-	$\times 0.2$	v	VD=1.0V±0.13V	
input	V _{ILX0AS}	X0A	External clock in	V _{SS}		V _{CC}	v		
voltage	V ILX0AS	AUA	"Oscillation mode"	- 0.3	-	$\times 0.2$	v		
voltage	V _{ILR}	RSTX		V _{SS}		V_{CC}	v	CMOS Hysteresis	
	V ILR	КЭТА	-	- 0.3	-	$\times 0.2$	v	input	
	V _{ILM}	MD		V _{SS}		V _{SS}	v	CMOS Hysteresis	
	V ILM		-	- 0.3	-	+ 0.3	v	input	
	V _{ILD}	DEBUG	_	V_{SS}		0.8	v	TTL Input	
	V ILD	I/F	-	- 0.3	-	0.0	v	I I L IIIput	

Deremeter	Symbol	Pin	Conditiona		Value	!	Linit	Domorko
Parameter	Symbol	name	Conditions	Min Typ Max Uni		Unit	Remarks	
			$4.5V{\leq}(D)V_{CC}{\leq}5.5V$					
	V_{OH4}	4mA	$I_{OH} = -4mA$	(D)V _{CC}	-	(D)V _{CC}	v	
	0111	type	$2.7V \le (D)V_{CC} < 4.5V$	- 0.5		() 60		
			$I_{OH} = -1.5 \text{mA}$ $4.5 \text{V} \le \text{DV}_{CC} \le 5.5 \text{V}$					
			$I_{OH} = -52mA$					
			$2.7V \le DV_{CC} < 4.5V$					$T_A = -40^{\circ}C$
			$I_{OH} = -18 \text{mA}$					
			$4.5V \le DV_{CC} \le 5.5V$					
			$I_{OH} = -39 mA$	-				$T_A = +25^{\circ}C$
"H" level		High	$2.7\mathrm{V} \le \mathrm{DV}_{\mathrm{CC}} < 4.5\mathrm{V}$	DU				
output	V _{OH30}	Drive	$I_{OH} = -16mA$	DV _{CC} - 0.5	-	DV _{CC}	V	
voltage		type*	$4.5V \le DV_{CC} \le 5.5V$ $I_{OH} = -32mA$	- 0.5				
			$2.7V \le DV_{CC} < 4.5V$					$T_A = +85^{\circ}C$
			$I_{OH} = -14.5 \text{mA}$					
			$4.5V \le DV_{CC} \le 5.5V$	-				_
			$I_{OH} = -30 mA$	_				$T_{A} = +105^{\circ}C$
			$2.7V \leq DV_{CC} < 4.5V$					$I_{\rm A} = +105$ C
			$I_{OH} = -14mA$					
	V _{OH3}	2	$4.5V \le V_{CC} \le 5.5V$	V _{CC} - 0.5		V _{CC}	v	
		3mA	$\frac{I_{OH} = -3mA}{2.7V \le V_{CC} < 4.5V}$		-			
		type	$I_{OH} = -1.5 \text{mA}$	- 0.5				
		$4.5V \le (D)V_{CC} \le 5.5V$						
	V	4mA	$I_{OL} = +4mA$			0.4	v	
	V _{OL4}	type	$2.7V{\leq}(D)V_{CC}{<}4.5V$	-	-	0.4	V	
			$I_{OL} = +1.7 \text{mA}$					
			$4.5V \le DV_{CC} \le 5.5V$					
			$I_{OL} = +52mA$	-				$T_A = -40^{\circ}C$
			$\begin{array}{l} 2.7V \leq DV_{CC} < 4.5V \\ I_{OL} = +22mA \end{array}$					
			$4.5V \le DV_{CC} \le 5.5V$	_				
			$I_{OL} = +39 \text{mA}$					T
"T " 1 1		II: -h	$2.7V \le DV_{CC} < 4.5V$					$T_A = +25^{\circ}C$
"L" level output	V _{OL30}	High Drive	$I_{OL} = +18 mA$		_	0.5	v	
voltage	• OL30	type*	$4.5V \leq DV_{CC} \leq 5.5V$		_	0.5	v	
, orage		- 7 F -	$I_{OL} = +32mA$	-				$T_A = +85^{\circ}C$
			$2.7V \le DV_{CC} < 4.5V$					
			$\frac{I_{OL} = +14mA}{4.5V \le DV_{CC} \le 5.5V}$					
			$4.5 \text{ V} \le D \text{ V}_{CC} \le 5.5 \text{ V}$ $I_{OL} = +30 \text{mA}$					
			$\frac{10L}{2.7V} \le DV_{CC} < 4.5V$	1				$T_A = +105^{\circ}C$
			$I_{OL} = +13.5 \text{mA}$					
	V	3mA	$2.7V \le V_{CC} < 5.5V$			0.4	v	
	V _{OL3}	type	$I_{OL} = +3mA$	-	-	0.4	v	
	V _{OLD}	DEBUG	$V_{\rm CC} = 2.7 V$	0	-	0.25	v	
	ULD	I/F	$I_{OL} = +25 mA$	~				

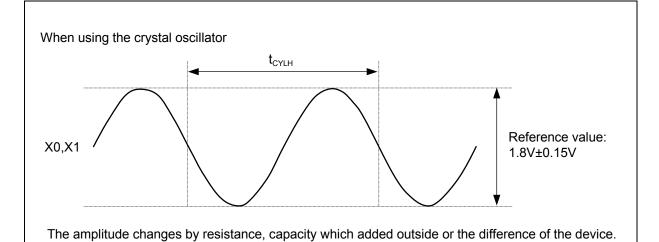
Deremeter	Cumbal	Din nome	Conditions		Value		Linit	Domorko
Parameter	Symbol	Pin name	Conditions	Min	Тур	Max	Unit	Remarks
Input leak	I _{IL}	Pnn_m	$\label{eq:VSS} \begin{split} V_{SS} &< V_{I} < V_{CC} \\ AV_{SS} < V_{I} < \\ AV_{CC}, AVRH \end{split}$	- 1	-	+ 1	μΑ	Single port pin except high current output I/O for SMC
current		P08_m	$\begin{array}{c} DV_{SS} < V_{I} < DV_{CC} \\ AV_{SS} < V_{I} < \\ AV_{CC}, AVRH \end{array}$	- 3	-	+ 3	μΑ	
Total LCD leak current	$\Sigma I_{ILCD} $	All SEG/ COM pin	$V_{\rm CC} = 5.0 V$	-	0.5	10	μΑ	Maximum leakage current of all LCD pins
Internal LCD divide resistance	R _{LCD}	Between V3 and V2, V2 and V1, V1 and V0	$V_{\rm CC} = 5.0 V$	6.25	12.5	25	kΩ	
Pull-up resistance value)		$V_{CC} = 5.0V \pm 10\%$	25	50	100	kΩ	
Pull-down resistance value	R _{DOWN}	P08_m	$V_{CC} = 5.0V \pm 10\%$	25	50	100	kΩ	
Input capacitance	C _{IN}	Other than C, Vcc, Vss, DVcc DVss, AVcc, AVss, AVRH, P08_m	-	-	5	15	pF	
			-	-	15	30	pF	

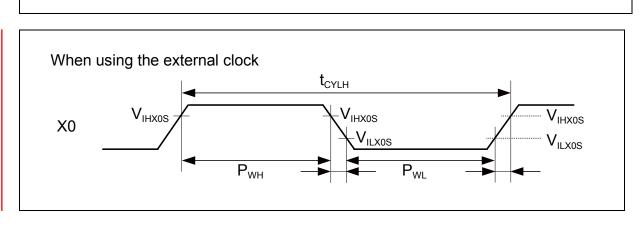
*: In the case of driving stepping motor directly or high current outputs, set "1" to the bit in the Port High Drive Register (PHDRnn:HDx="1").

4. AC Characteristics

(1) Main Clock Input Characteristics

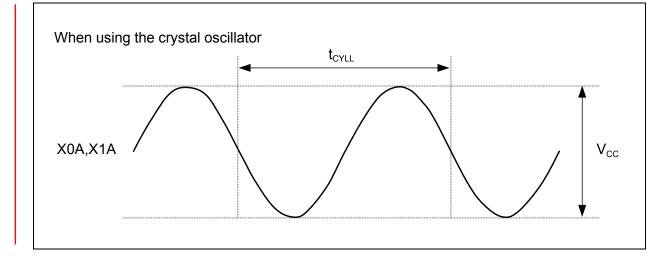
$(V_{CC} = AV_{CC} = I$	$OV_{CC} = 2.7V$	to 5.5V, V	D=1.8V±0).15V, V _{SS}	$= AV_{SS} =$	$DV_{SS} = 0$	$V, T_{\rm A} = -40^{\circ}{\rm C} \text{ to} + 105^{\circ}{\rm C})$
Parameter	Symbol	Pin		Value		Unit	Remarks
Farameter	Symbol	name	Min	Тур	Max	Unit	Remarks
			4	-	8	MHz	When using a crystal oscillator, PLL off
Input frequency	f _C	X0, X1	-	-	8	MHz	When using an opposite phase external clock, PLL off
		AI	4	-	8	MHz	When using a crystal oscillator or opposite phase external clock, PLL on
Innut for monor	£	VO	-	-	8	MHz	When using a single phase external clock in "Fast Clock Input mode", PLL off
Input frequency	f _{FCI}	X0	4	-	8	MHz	When using a single phase external clock in "Fast Clock Input mode", PLL on
Input clock cycle	t _{CYLH}	-	125	-	-	ns	
Input clock pulse width	P _{WH} , P _{WL}	-	55	-	-	ns	

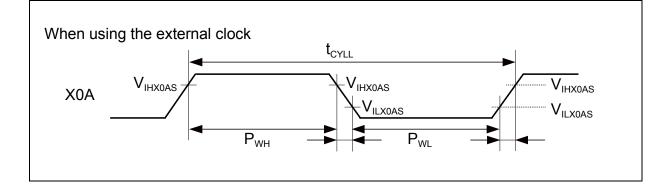




(1) eas electric	•		$DV_{CC} = 2.7V$ to	5.5V, V	$_{\rm SS} = AV_{\rm SS} =$	= DV _{SS} =	0V, T _A	$= -40^{\circ}$ C to $+105^{\circ}$ C)
Parameter	Symbol	Pin	Conditions		Value		Unit	Remarks
Farameter	Symbol	name	Conditions	Min	Тур	Max	Onit	INCIDAINS
		X0A,	-	-	32.768	-	kHz	When using an oscillation circuit
Input frequency	nput frequency f _{CL}		-	-	-	100	kHz	When using an opposite phase external clock
		X0A	-	-	-	50	kHz	When using a single phase external clock
Input clock cycle	t _{CYLL}	-	-	10	-	-	μs	
Input clock pulse width	-	-	$\begin{array}{l} P_{WH}/t_{CYLL},\\ P_{WL}/t_{CYLL} \end{array}$	30	-	70	%	

(2) Sub Clock Input Characteristics





(3) Built-in RC Oscillation Characteristics

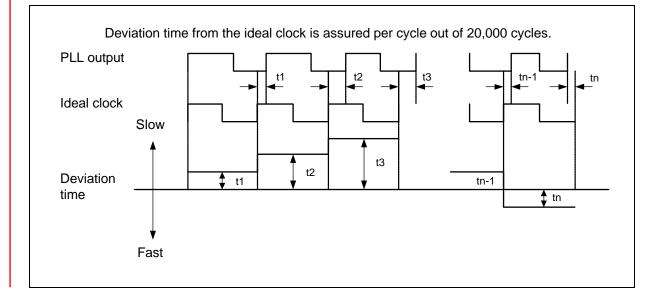
	$(V_{CC} = AV_C)$	$C = DV_{CC} =$	= 2.7V to 5.1	5V, $V_{SS} = A$	$AV_{SS} = DV$	$_{\rm SS} = 0$ V, $T_{\rm A} = -40^{\circ}$ C to $+105^{\circ}$ C)
Parameter	Symbol		Value		Unit	Remarks
Farameter	Symbol	Min	Тур	Max	Unit	Remarks
Clock frequency	f	50	100	200	kHz	When using slow frequency of RC oscillator
Clock frequency	f _{RC}	1	2	4	MHz	When using fast frequency of RC oscillator
RC clock stabilization	t	80	160	320	μs	When using slow frequency of RC oscillator (16 RC clock cycles)
time	t _{RCSTAB}	64	128	256	μs	When using fast frequency of RC oscillator (256 RC clock cycles)

(4) Internal Clock Timing

$(V_{CC} = AV_{CC} = DV_{CC} = 2$	$2.7V$ to 5.5V, $V_{SS} = AV_{SS} =$	$DV_{SS} = 0V, T$	$T_{\rm A} = -40^{\circ}{\rm C}$ to -	+ 105°C)
Parameter	Symbol	Va	Unit	
Falametei	Symbol	Min	Unit	
Internal System clock frequency (CLKS1 and CLKS2)	f _{CLKS1} , f _{CLKS2}	-	54	MHz
Internal CPU clock frequency (CLKB), Internal peripheral clock frequency (CLKP1)	f _{CLKB} , f _{CLKP1}	-	32	MHz
Internal peripheral clock frequency (CLKP2)	f _{CLKP2}	-	32	MHz

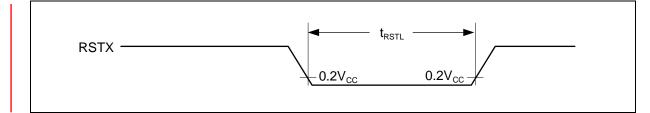
(5) Operating Conditions of PLL

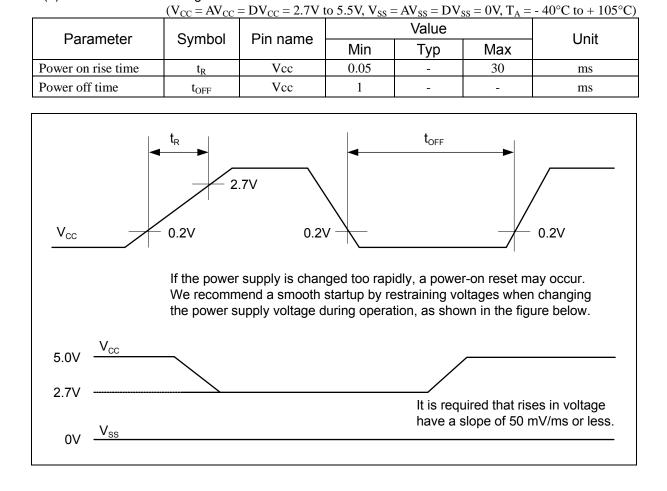
$(V_{CC} = AV_{CC} = DV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = DV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 10^{\circ}C$						$DV, T_A = -40^{\circ}C \text{ to } + 105^{\circ}C)$
Parameter	Symbol	Value		Unit	Remarks	
	Symbol	Min	Тур	Max	Unit	Remarks
PLL oscillation stabilization wait time	t _{LOCK}	1	-	4	ms	For CLKMC = 4MHz
PLL input clock frequency	f _{PLLI}	4	-	8	MHz	
PLL oscillation clock frequency	f _{CLKVCO}	56	-	108	MHz	Permitted VCO output frequency of PLL (CLKVCO)
PLL phase jitter	t _{PSKEW}	-5	-	+5	ns	For CLKMC (PLL input clock) \ge 4MHz



(6) Reset Input

$(V_{CC} = AV_{CC} = DV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = DV_{SS} = 0V, T_A = -40^{\circ}\text{C to} + 105^{\circ}\text{C})$							
Parameter	Symbol	Pin name	Va	Unit			
T diameter	Cymbol	1 III Hame	Min	Max	Onit		
Reset input time	4	RSTX	10	-	μs		
Rejection of reset input time	t _{RSTL}	K) I A	1	-	μs		





(7) Power-on Reset Timing

(8) USART Timing

T

$(V_{CC} = AV_{CC} = DV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = DV_{SS} = 0V, T_A = -40^{\circ}\text{C to} + 105^{\circ}\text{C}, C_L = 50\text{pF})$								
Baramatar	Symbol	Pin	Conditions	$4.5V \leq V_C$	_C < 5.5V	$2.7V \leq V_{C}$	_C < 4.5V	Linit
Parameter	Symbol	name		Min	Max	Min	Max	Unit
Serial clock cycle time	t _{SCYC}	SCKn		4t _{CLKP1}	-	4t _{CLKP1}	-	ns
$SCK \downarrow \rightarrow SOT$ delay time	t _{SLOVI}	SCKn, SOTn		- 20	+ 20	- 30	+ 30	ns
SOT \rightarrow SCK \uparrow delay time	t _{ovshi}	SCKn, SOTn	Internal shift	$N \times t_{CLKP1} - 20^*$	-	$N \times t_{CLKP1} - 30^*$	-	ns
SIN \rightarrow SCK \uparrow setup time	t _{IVSHI}	SCKn, SINn	clock mode	t _{CLKP1} + 45	-	t _{CLKP1} + 55	-	ns
SCK $\uparrow \rightarrow$ SIN hold time	t _{SHIXI}	SCKn, SINn		0	-	0	-	ns
Serial clock "L" pulse width	t _{SLSH}	SCKn		t _{CLKP1} + 10	-	t _{CLKP1} + 10	-	ns
Serial clock "H" pulse width	t _{SHSL}	SCKn		t _{CLKP1} + 10	-	t _{CLKP1} + 10	-	ns
SCK $\downarrow \rightarrow$ SOT delay time	t _{SLOVE}	SCKn, SOTn	External shift	-	$2t_{CLKP1} + 45$	-	2t _{CLKP1} + 55	ns
SIN \rightarrow SCK \uparrow setup time	t _{IVSHE}	SCKn, SINn	clock mode	t _{CLKP1} /2 + 10	-	t _{CLKP1} /2 + 10	-	ns
SCK $\uparrow \rightarrow$ SIN hold time	t _{SHIXE}	SCKn, SINn		t _{CLKP1} + 10	-	t _{CLKP1} + 10	-	ns
SCK fall time	t _F	SCKn		-	20	-	20	ns
SCK rise time	t _R	SCKn		-	20	-	20	ns

Notes: • AC characteristic in CLK synchronized mode.

 \bullet C_L is the load capacity value of pins when testing.

• Depending on the used machine clock frequency, the maximum possible baud rate can be limited by some parameters. These parameters are shown in "MB96600 series HARDWARE MANUAL".

• t_{CLKP1} indicates the peripheral clock 1 (CLKP1), Unit: ns

• These characteristics only guarantee the same relocate port number.

For example, the combination of SCKn and SOTn_R is not guaranteed.

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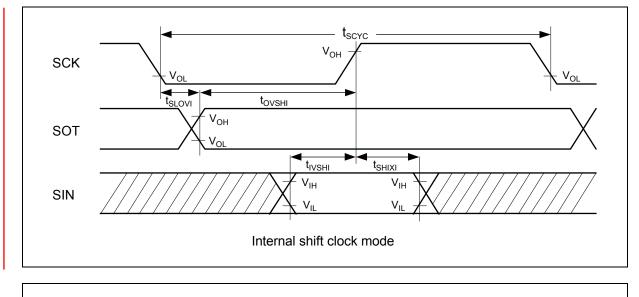
*: Parameter N depends on $t_{\mbox{\scriptsize SCYC}}$ and can be calculated as follows:

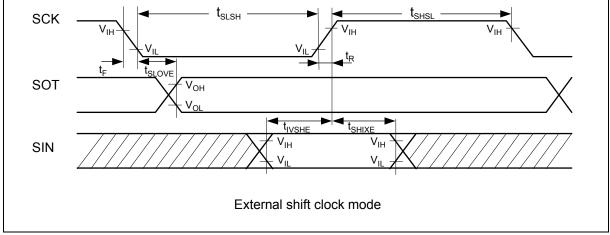
• If $t_{SCYC} = 2 \times k \times t_{CLKP1}$, then N = k, where k is an integer > 2

• If $t_{SCYC} = (2 \times k + 1) \times t_{CLKP1}$, then N = k + 1, where k is an integer > 1

Examples:

t _{SCYC}	Ν
$4 \times t_{CLKP1}$	2
$5 \times t_{CLKP1}, 6 \times t_{CLKP1}$	3
$7 \times t_{CLKP1}, 8 \times t_{CLKP1}$	4

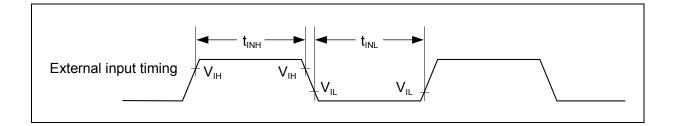




(9) External Input Timing

	$(V_{CC} = A)$	$AV_{CC} = DV_{CC} = 2.7V$	V to 5.5V, $V_{SS} = A^{2}$	$V_{SS} = DV$	$V_{\rm SS} = 0$	$T_{\rm A} = -40^{\circ}{\rm C} \text{ to} + 105^{\circ}{\rm C}$	
Parameter	Symbol	Pin name	Value		Unit	Remarks	
Falameter	Symbol	Fill Hallie	Min	Max	Unit	Remarks	
		Pnn_m		General Purpose I/O			
			ADTG				A/D Converter trigger
						input	
		TINn, TINn_R	$2t_{\text{CLKP1}} + 200$			Reload Timer	
		TTGn	$(t_{CLKP1} = 1/f_{CLKP1})*$	-	ns	PPG trigger input	
Input pulse width	t _{INH} , t _{INL}		FRCKn,	1/1 _{CLKP1})			Free-Running Timer
		^{INL} FRCKn_R			input clock		
		INn, INn_R				Input Capture	
		INTn, INTn_R				External Interrupt	
		NMI	200	-	ns	Non-Maskable	
		1 (1)11				Interrupt	

*: t_{CLKP1} indicates the peripheral clock1 (CLKP1) cycle time except stop when in stop mode.



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(10) I²C Timing

(V _{CC} =	$AV_{CC} = DV$	$_{\rm CC} = 2.7 {\rm V}$ to 5.5 {\rm V},	$V_{SS} = AV_S$	$s_{s} = DV_{ss} =$	$0V, T_A = -$	-40° C to +	105°C)
Parameter	Symbol	Conditions	Туріса	l mode	High- mo	Unit	
			Min	Max	Min	Max	
SCL clock frequency	f _{SCL}		0	100	0	400	kHz
(Repeated) START condition							
hold time	t _{HDSTA}		4.0	-	0.6	-	μs
$SDA \downarrow \rightarrow SCL \downarrow$							
SCL clock "L" width	t _{LOW}		4.7	-	1.3	-	μs
SCL clock "H" width	t _{HIGH}		4.0	-	0.6	-	μs
(Repeated) START condition					- ·		
setup time	t _{SUSTA}		4.7	-	0.6	-	μs
$\operatorname{SCL} \uparrow \to \operatorname{SDA} \downarrow$		$C_{L} = 50 pF,$ $R = (Vp/I_{OL})^{*1}$					
Data hold time	t _{HDDAT}	$\mathbf{R} = (\mathbf{V}\mathbf{p}/\mathbf{I}_{\rm OL})^{*}$	0	3.45^{*2}	0	0.9^{*^3}	μs
$\operatorname{SCL} \downarrow \to \operatorname{SDA} \downarrow \uparrow$							•
Data setup time	t _{SUDAT}		250	-	100	-	ns
$SDA \downarrow \uparrow \rightarrow SCL \uparrow$ STOP condition setup time							
STOP condition setup time $SCL \uparrow \rightarrow SDA \uparrow$	t _{SUSTO}		4.0	-	0.6	-	μs
Bus free time between							
"STOP condition" and	t _{BUS}		4.7	_	1.3	_	μs
"START condition"	CBUS		1.7		1.5		μο
Pulse width of spikes which				(1.1.5)		(1.1.5)	
will be suppressed by input	t _{SP}	-	0	$(1-1.5) \times$	0	$(1-1.5) \times$	ns
noise filter				t _{CLKP1} * ⁵		t _{CLKP1} * ⁵	

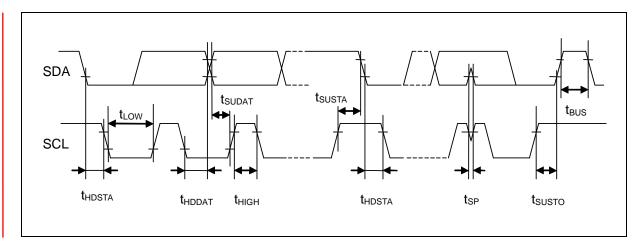
*1: R and C_L represent the pull-up resistance and load capacitance of the SCL and SDA lines, respectively. Vp indicates the power supply voltage of the pull-up resistance and I_{OL} indicates V_{OL} guaranteed current.

*2: The maximum t_{HDDAT} only has to be met if the device does not extend the "L" width (t_{LOW}) of the SCL signal.

*3: A high-speed mode I²C bus device can be used on a standard mode I²C bus system as long as the device satisfies the requirement of " $t_{SUDAT} \ge 250$ ns".

*4: For use at over 100kHz, set the peripheral clock1 (CLKP1) to at least 6MHz.

*5: t_{CLKP1} indicates the peripheral clock1 (CLKP1) cycle time.



5. A/D Converter

(1) Electrical Characteristics for the A/D Converter

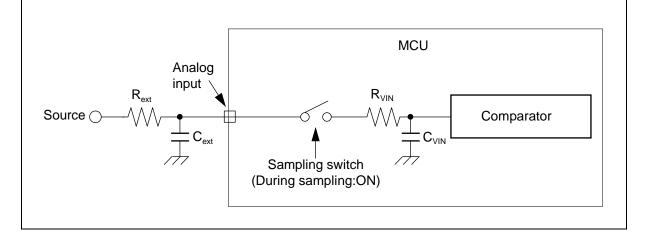
	$(V_{CC} = A)$	$AV_{CC} = DV_{CC}$	= 2.7 V to 5		$V_{SS} = DV_{SS}$	= 0V, T	$T_{\rm A} = -40^{\circ}{\rm C} \text{ to} + 105^{\circ}{\rm C}$
Parameter	Symbol	Pin		Value		Unit	Remarks
T arameter	Oymbol	name	Min	Тур	Max	Onit	Remarks
Resolution	-	-	-	-	10	bit	
Total error	-	-	- 3.0	-	+ 3.0	LSB	
Nonlinearity error	-	-	- 2.5	-	+ 2.5	LSB	
Differential Nonlinearity error	-	-	- 1.9	-	+ 1.9	LSB	
Zero transition voltage	V _{OT}	ANn	Тур - 20	$\begin{array}{c} AV_{SS} \\ + \ 0.5LSB \end{array}$	Typ + 20	mV	
Full scale transition voltage	V _{FST}	ANn	Тур - 20	AVRH - 1.5LSB	Typ + 20	mV	
Compare time [*]	-		1.0	-	5.0	μs	$4.5V \leq AV_{CC} \leq 5.5V$
Compare unie	-	-	2.2	-	8.0	μs	$2.7V \leq AV_{CC} < 4.5V$
Sampling time [*]	-		0.5	-	-	μs	$4.5V \leq AV_{CC} \leq 5.5V$
Sampning time	-	-	1.2	-	-	μs	$2.7V \leq AV_{CC} < 4.5V$
Power supply	I _A		-	2.0	3.1	mA	A/D Converter active
current	I _{AH}	AV _{CC}	-	-	3.3	μΑ	A/D Converter not operated
Reference power supply current	I _R		-	520	810	μΑ	A/D Converter active
(between AVRH and AV_{SS})	I _{RH}	AVRH	-	-	1.0	μΑ	A/D Converter not operated
Analog input	C	AN8 to 13	-	-	15.5	pF	Normal outputs
capacity	C_{VIN}	AN16 to 23	-	-	17.4	pF	High current outputs
Analog impadance	D	ANn	-	-	1450	Ω	$4.5V{\leq}AV_{CC}{\leq}5.5V$
Analog impedance	R _{VIN}	Ami	-	-	2700	Ω	$2.7V{\leq}AV_{CC}{<}4.5V$
Analog port input		AN8 to 13	- 1.0	-	+ 1.0	μA	AV _{SS} < V _{AIN} <
current (during conversion)	I _{AIN}	AN16 to 23	- 3.0	-	+ 3.0	μΑ	$AV_{SS} < V_{AIN} < AV_{CC}, AVRH$
Analog input voltage	V _{AIN}	ANn	AV _{SS}	-	AVRH	V	
Reference voltage range	-	AVRH	AV _{CC} - 0.1	-	AV _{CC}	V	
Variation between channels	-	ANn	-	-	4.0	LSB	

*: Time for each channel.

(2) Accuracy and Setting of the A/D Converter Sampling Time

If the external impedance is too high or the sampling time too short, the analog voltage charged to the internal sample and hold capacitor is insufficient, adversely affecting the A/D conversion precision.

To satisfy the A/D conversion precision, a sufficient sampling time must be selected. The required sampling time (Tsamp) depends on the external driving impedance R_{ext} , the board capacitance of the A/D converter input pin C_{ext} and the AV_{CC} voltage level. The following replacement model can be used for the calculation:



Rext: External driving impedance

Cext: Capacitance of PCB at A/D converter input

C_{VIN}: Analog input capacity (I/O, analog switch and ADC are contained)

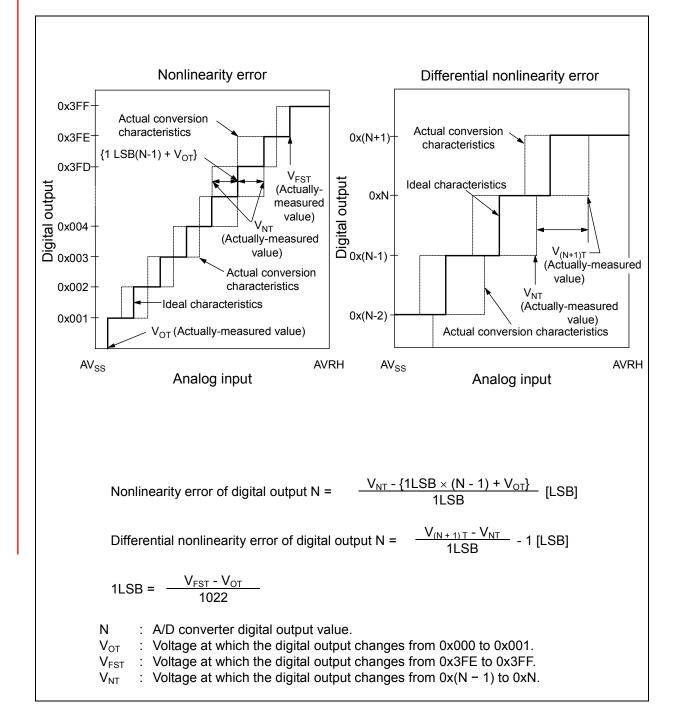
R_{VIN}: Analog input impedance (I/O, analog switch and ADC are contained)

The following approximation formula for the replacement model above can be used: $Tsamp = 7.62 \times (Rext \times Cext + (Rext + R_{VIN}) \times C_{VIN})$

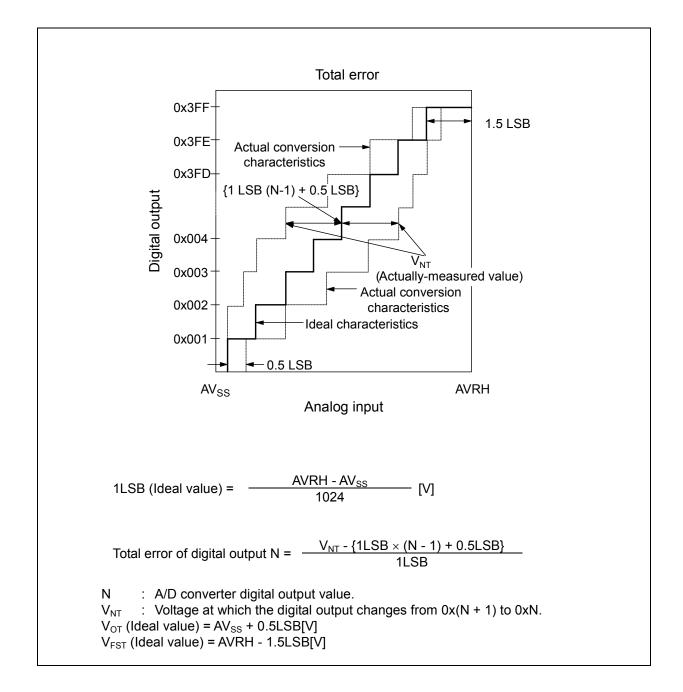
- Do not select a sampling time below the absolute minimum permitted value. $(0.5\mu s \text{ for } 4.5V \le AV_{CC} \le 5.5V, 1.2\mu s \text{ for } 2.7V \le AV_{CC} < 4.5V)$
- If the sampling time cannot be sufficient, connect a capacitor of about 0.1µF to the analog input pin.
- A big external driving impedance also adversely affects the A/D conversion precision due to the pin input leakage current IIL (static current before the sampling switch) or the analog input leakage current IAIN (total leakage current of pin input and comparator during sampling). The effect of the pin input leakage current IIL cannot be compensated by an external capacitor.
- \bullet The accuracy gets worse as |AVRH $AV_{SS}|$ becomes smaller.

(3) Definition of A/D Converter Terms

- Resolution : Analog variation that is recognized by an A/D converter.
- Nonlinearity error : Deviation of the actual conversion characteristics from a straight line that connects the zero transition point (0b000000000 $\leftarrow \rightarrow$ 0b000000001) to the full-scale
- transition point (0b111111110 $\leftarrow \rightarrow$ 0b111111111). • Differential nonlinearity error : Deviation from the ideal value of the input voltage that is required to
 - change the output code by 1LSB.
- •Total error : Difference between the actual value and the theoretical value. The total error includes zero transition error, full-scale transition error and nonlinearity error.
- Zero transition voltage: Input voltage which results in the minimum conversion value.
- Full scale transition voltage: Input voltage which results in the maximum conversion value.

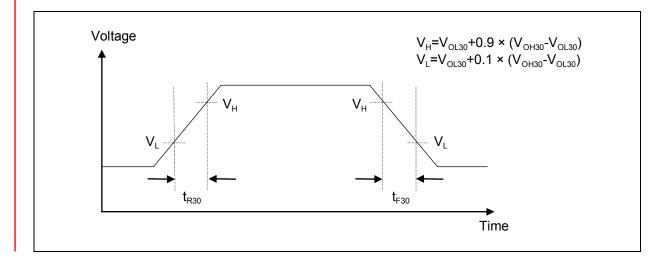


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6. High Current Output Slew Rate

	(V _{CC}	$= AV_{CC} =$	$DV_{CC} = 2.7V$ to	5.5V, V _s	$s = AV_{SS} =$	$DV_{SS} = 0$	V, $T_A =$	-40° C to $+105^{\circ}$ C)
Parameter	Symbol	Pin	Conditions	Value		lue		Demerke
Falameter	Symbol	name	Conditions	Min	Тур	Max	Unit	Remarks
Output rise/fall time	t _{R30} , t _{F30}	P08_m	Outputs driving strength set to "30mA"	15	-	75	ns	C _L =85pF



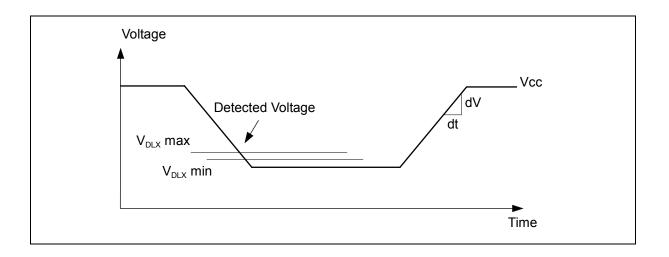
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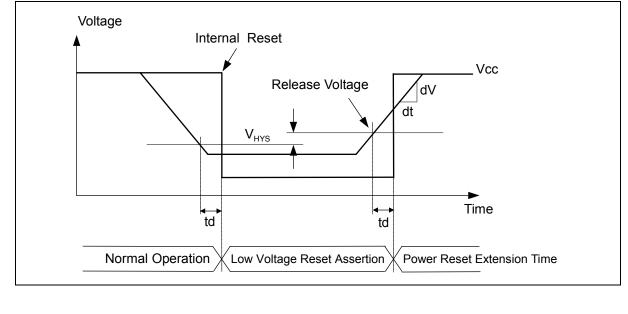
($V_{CC} = AV_{CC} =$	$DV_{CC} = 2.7V$ to 5.5V, $V_{SS} = A$	$V_{SS} = DV_{SS}$	$ = 0V, T_{\rm A} =$	$= -40^{\circ}$ C to +	105°C)	
Parameter	Symbol	Conditions		Unit			
Farameter	Symbol	Conditions	Min	Тур	Max	Onit	
	V _{DL0}	$CILCR:LVL = 0000_B$	2.70	2.90	3.10	V	
	V _{DL1}	$CILCR:LVL = 0001_B$	2.79	3.00	3.21	V	
	V _{DL2}	$CILCR:LVL = 0010_B$	2.98	3.20	3.42	V	
Detected voltage ^{*1}	V _{DL3}	$CILCR:LVL = 0011_B$	3.26	3.50	3.74	V	
	V _{DL4}	$CILCR:LVL = 0100_B$	3.45	3.70	3.95	V	
	V _{DL5}	$CILCR:LVL = 0111_B$	3.73	4.00	4.27	V	
	V _{DL6}	$CILCR:LVL = 1001_B$	3.91	4.20	4.49	V	
Power supply voltage change rate ^{*2}	dV/dt	-	- 0.004	-	+ 0.004	V/µs	
TT / 1/1	X 7	CILCR:LVHYS=0	-	-	50	mV	
Hysteresis width	V_{HYS}	CILCR:LVHYS=1	80	100	120	mV	
Stabilization time	T _{lvdstab}	-	-	-	75	μs	
Detection delay time	t _d	-	-	-	30	μs	

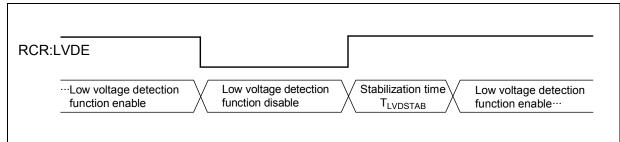
7. Low Voltage Detection Function Characteristics

*1: If the power supply voltage fluctuates within the time less than the detection delay time (t_d), there is a possibility that the low voltage detection will occur or stop after the power supply voltage passes the detection range.

*2: In order to perform the low voltage detection at the detection voltage (V_{DLX}), be sure to suppress fluctuation of the power supply voltage within the limits of the change ratio of power supply voltage.







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8. Flash Memory Write/Erase Characteristics

	$(V_{CC} = AV_{CC} = DV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = DV_{SS} = 0V, T_A = -40^{\circ}\text{C to} + 105^{\circ}\text{C}$						
Paran	notor	Conditions		Value	9	Unit	Remarks
Falai	netei	Conditions	Min	Тур	Max	Unit	Remarks
	Large Sector	-	-	1.6	7.5	S	Includes units time
Sector erase time	Small Sector	-	-	0.4	2.1	S	Includes write time prior to internal erase.
	Security Sector	-	-	0.31	1.65	S	prior to internar erase.
							Not including
Word (16-bit) writ	te time	-	-	25	400	μs	system-level overhead
							time.
Chip grass time				5.11	25.05	c	Includes write time
Chip erase time	Chip erase time		-	5.11	25.05	S	prior to internal erase.

Note: While the Flash memory is written or erased, shutdown of the external power (V_{CC}) is prohibited. In the application system where the external power (V_{CC}) might be shut down while writing or erasing, be sure to turn the power off by using a low voltage detection function.

To put it concrete, change the external power in the range of change ration of power supply voltage $(-0.004V/\mu s \text{ to } +0.004V/\mu s)$ after the external power falls below the detection voltage $(V_{DLX})^{*1}$.

Write/Erase cycles and data hold time

Write/Erase cycles	Data hold time						
(cycle)	(year)						
1,000	20 *2						
10,000	10 *2						
100,000	5 *2						

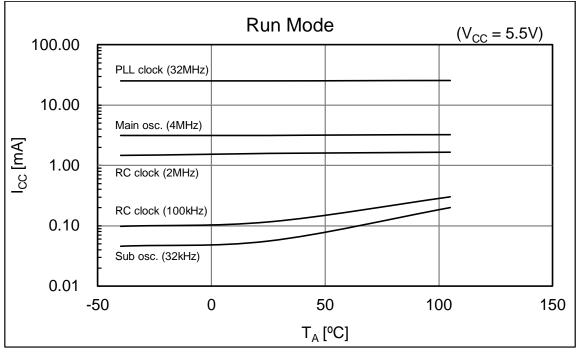
*1: See "7. Low Voltage Detection Function Characteristics".

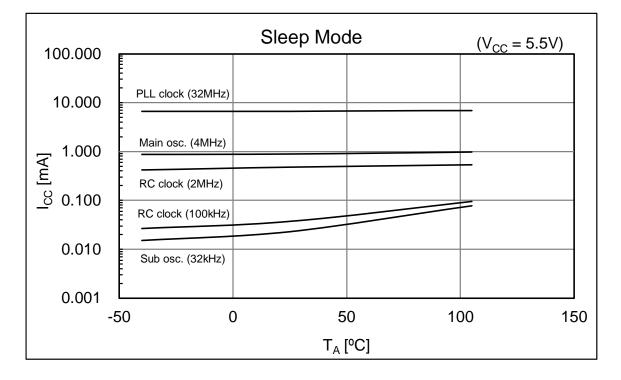
*2: This value comes from the technology qualification (using Arrhenius equation to translate high temperature measurements into normalized value at + 85°C).

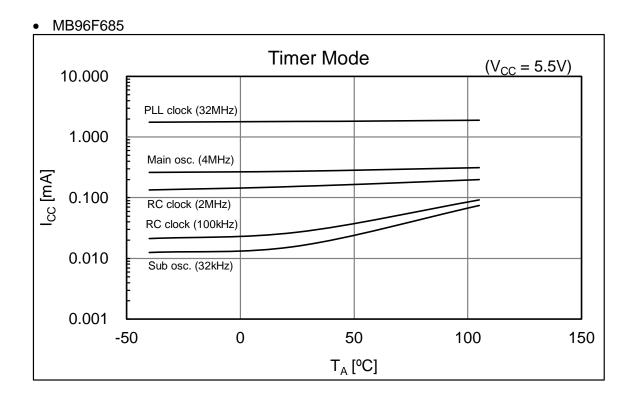
EXAMPLE CHARACTERISTICS

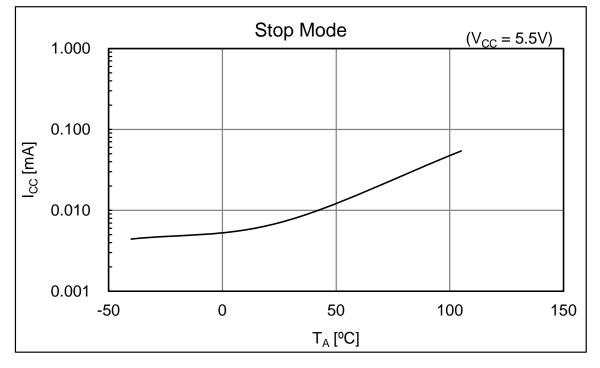
This characteristic is an actual value of the arbitrary sample. It is not the guaranteed value.

• MB96F685









• Used setting

Mode	Selected Source Clock	Clock/Regulator and FLASH Settings
Run mode	PLL	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 32MHz
	Main osc.	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 4MHz
	RC clock fast	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 2MHz
	RC clock slow	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 100kHz
	Sub osc.	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 32kHz
Sleep mode	PLL	CLKS1 = CLKS2 = CLKB1 = CLKP2 = 32MHz
Sleep mode	FLL	Regulator in High Power Mode,
		(CLKB is stopped in this mode)
	Main osc.	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 4MHz
		Regulator in High Power Mode,
		(CLKB is stopped in this mode)
	RC clock fast	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 2MHz
		Regulator in High Power Mode,
		(CLKB is stopped in this mode)
	RC clock slow	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 100kHz
		Regulator in Low Power Mode,
		(CLKB is stopped in this mode)
	Sub osc.	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 32kHz
		Regulator in Low Power Mode,
Τ'		(CLKB is stopped in this mode)
Timer mode	PLL	CLKMC = 4MHz, CLKPLL = 32MHz (System clocks are stopped in this mode)
		Regulator in High Power Mode,
		FLASH in Power-down / reset mode
	Main osc.	CLKMC = 4MHz
	Wall Ose.	(System clocks are stopped in this mode)
		Regulator in High Power Mode,
		FLASH in Power-down / reset mode
	RC clock fast	CLKMC = 2MHz
		(System clocks are stopped in this mode)
		Regulator in High Power Mode,
		FLASH in Power-down / reset mode
	RC clock slow	CLKMC = 100kHz
		(System clocks are stopped in this mode)
		Regulator in Low Power Mode,
		FLASH in Power-down / reset mode
	Sub osc.	CLKMC = 32 kHz
		(System clocks are stopped in this mode)
		Regulator in Low Power Mode,
<u>a.</u> 1		FLASH in Power-down / reset mode
Stop mode	stopped	(All clocks are stopped in this mode)
		Regulator in Low Power Mode,
		FLASH in Power-down / reset mode

ORDERING INFORMATION

MCU with CAN controller

Part number	Flash memory	Package*
MB96F683RBPMC-GSE1	Flash A	80-pin plastic LQFP
MB96F683RBPMC-GSE2	(96.5KB)	(FPT-80P-M21)
MB96F685RBPMC-GSE1	Flash A	80-pin plastic LQFP
MB96F685RBPMC-GSE2	(160.5KB)	(FPT-80P-M21)

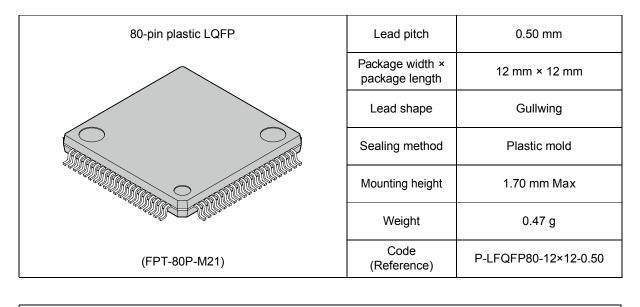
*: For details about package, see "
PACKAGE DIMENSION".

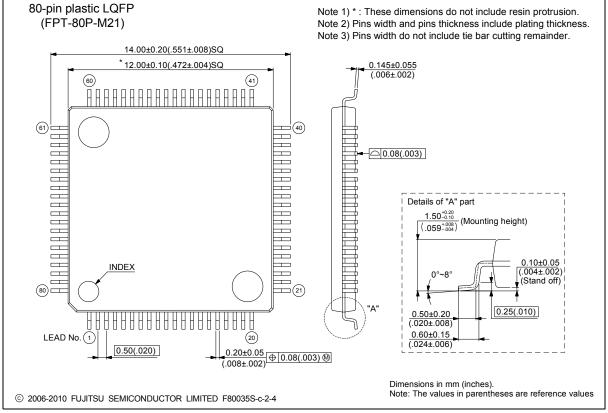
MCU without CAN controller

Part number	Flash memory	Package*
MB96F683ABPMC-GSE1	Flash A	80-pin plastic LQFP
MB96F683ABPMC-GSE2	(96.5KB)	(FPT-80P-M21)
MB96F685ABPMC-GSE1	Flash A	80-pin plastic LQFP
MB96F685ABPMC-GSE2	(160.5KB)	(FPT-80P-M21)

*: For details about package, see "■PACKAGE DIMENSION".

PACKAGE DIMENSION





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Please check the latest package dimension at the following URL. http://edevice.fujitsu.com/package/en-search/

■ MAJOR CHANGES IN THIS EDITION

Page	Section	Change Results
-	-	PRELIMINARY \rightarrow Data sheet
2	FEATURES	Changed the description of "System clock" Up to 16 MHz external clock for devices with fast clock input feature → Up to 8 MHz external clock for devices with fast clock input feature
		Changed the description of "LCD Controller" On-chip drivers for internal divider resistors or external divider resistors →
4		Internal divider resistors or external divider resistors Changed the description of "External Interrupts" Interrupt mask and pending bit per channel →
	-	Interrupt mask bit per channel
5		Changed the description of "Built-in On Chip Debugger" - Event sequencer: 2 levels →
		- Event sequencer: 2 levels + reset
6	■PRODUCT LINEUP	Changed the Remark of RLT RLT 1/2/6 Only RLT6 can be used as PPG clock source → RLT 1/2/6
	■BLOCK DIAGRAM	Deleted the block of RLT6 from PPG block
7		Changed the RLT block 2ch \rightarrow
		1/2/6 3ch
9	■PIN DESCRIPTION	Changed the Description of PPGn_B Programmable Pulse Generator n output (8bit) → Programmable Pulse Generator n output pin (16bit/8bit)
	■I/O CIRCUIT TYPE	Changed the figure of type B
14		Changed the Remarks of type B (CMOS hysteresis input with input shutdown function, $I_{OL} = 4mA$, $I_{OH} = -4mA$, Programmable pull-up resister) \rightarrow (CMOS level output ($I_{OL} = 4mA$, $I_{OH} = -4mA$), Automotive input with input shutdown function and programmable pull-up
15	-	resistor) Changed the figure of type G
15		Changed the figure of type of

A change on a page is indicated by a vertical line drawn on the left side of that page.

Page	Section	Change Results
19	■MEMORY MAP	Changed the START addresses of Boot-ROM $0F:E000_{H}$ \rightarrow $0F:C000_{H}$
21	USER ROM MEMORY MAP FOR FLASH DEVICES	Changed the annotation Others (from DF:0200 _H to DF:1FFF _H) are all mirror area of SAS-512B. \rightarrow Others (from DF:0200 _H to DF:1FFF _H) is mirror area of SAS-512B.
	■INTERRUPT VECTOR TABLE	Changed the Description of CALLV0 to CALLV7 Reserved →
		CALLV instruction Changed the Description of RESET Reserved → Reset vector
23		Changed the Description of INT9 Reserved → INT9 instruction
		Changed the Description of EXCEPTION Reserved \rightarrow
		Undefined instruction execution
		Changed the Vector name of Vector number 64 PPGRLT → RLT6
24		Changed the Description of Vector number 64 Reload Timer 6 can be used as PPG clock source → Reload Timer 6
27 to 30	■HANDLING PRECAUTIONS	Added a section
	HANDLING DEVICES	Added the description to "3. External clock usage" (3) Opposite phase external clock
32		Changed the description in "7. Turn on sequence of power supply to A/D converter and analog inputs" In this case, the voltage must not exceed AVRH or AV_{CC}
		In this case, AVRH must not exceed AV_{CC} . Input voltage for ports shared with analog input ports also must not exceed AV_{CC}
33		Changed the description in "11. SMC power supply pins" To avoid this, V_{CC} must always be powered on before DV_{CC} . \rightarrow To avoid this, V_{CC} must always be powered on before DV_{CC} . DV_{CC}/DV_{SS} must be applied when using SMC I/O pin as GPIO.
		Added the description "13. Mode Pin (MD)"



Page	Section	Change Results
	ELECTRICALCHARACTERISTICS1. Absolute Maximum Ratings	Changed the Value $\Sigma I_{CLAMP} $ Max: 19mA \rightarrow 21mA
34		Changed the Symbol of ""L" level average overall output current" $\Sigma I_{OLSMCAV}$ \rightarrow $\Sigma I_{OLAVSMC}$
		Changed the Symbol of ""H" level average overall output current" $\Sigma I_{OHSMCAV}$ \rightarrow
	ELECTRICAL CHARACTERISTICS 1. Absolute Maximum Ratings	$\begin{array}{l} \Sigma I_{OHAVSMC} \\ \hline \\ Changed the annotation *2 \\ It is required that AV_{CC} does not exceed V_{CC} and that the voltage at the analog inputs does not exceed AV_{CC} when the power is switched on. \\ \rightarrow \end{array}$
		It is required that AV_{CC} does not exceed V_{CC} , DV_{CC} and that the voltage at the analog inputs does not exceed AV_{CC} when the power is switched on. Changed the annotation *3
		Input/Output voltages of standard ports depend on V_{CC} .
		Input/Output voltages of high current ports depend on DV_{CC} . Input/Output voltages of standard ports depend on V_{CC} .
35		Changed the annotation *4 Note that if the +B input is applied during power-on, the power supply is provided from the pins and the resulting supply voltage may not be sufficient to operate the Power reset (except devices with persistent low voltage reset in internal vector mode). \rightarrow
		Note that if the +B input is applied during power-on, the power supply is provided from the pins and the resulting supply voltage may not be sufficient to operate the Power reset.
		Added the annotation *4 The DEBUG I/F pin has only a protective diode against V_{SS} . Hence it is only permitted to input a negative clamping current (4mA). For protection against positive input voltages, use an external clamping diode which limits the input voltage to maximum 6.0V.
37	2. Recommended Operating Conditions	Added the Value and Remarks to "Power supply voltage" Min: 2.0V Typ: - Max: 5.5V Remarks: Maintains RAM data in stop mode
		Changed the Value of "Smoothing capacitor at C pin" Typ: $1.0\mu F \rightarrow 1.0\mu F$ to $3.9\mu F$ Max: $1.5\mu F \rightarrow 4.7\mu F$
		Changed the Remarks of "Smoothing capacitor at C pin" Deleted "(Target value)" Added " 3.9μ F (Allowance within $\pm 20\%$)"

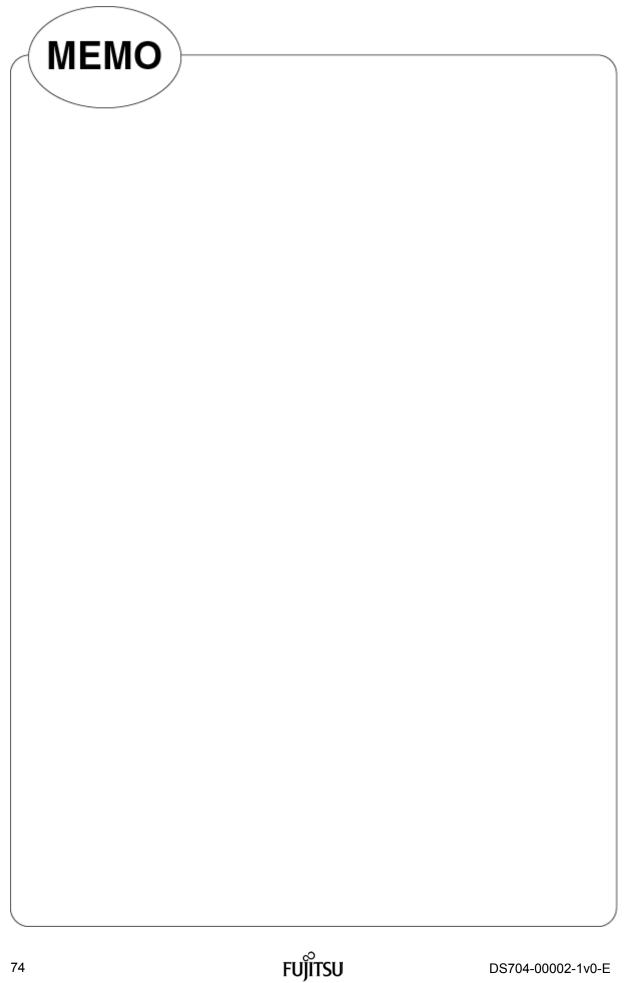
Page	Section	Change Results
	3. DC Characteristics	Deleted "(Target value)"
	(1) Current Rating	Added the Symbol to "Power supply current in Run modes" I _{CCRCH} , I _{CCRCL} Changed the Conditions of I _{CCPLL} , I _{CCMAIN} , I _{CCSUB} in "Power
		supply current in Run modes" "Flash 0 wait" is added
38		Changed the Value of "Power supply current in Run modes" I_{CCPLL} Max: 45mA \rightarrow 34mA ($T_A = +105^{\circ}C$) I_{CCMAIN}
		Max: $9mA \rightarrow 7.5mA (T_A = +105^{\circ}C)$ I_{CCSUB} Max: $6mA \rightarrow 3mA (T_A = +105^{\circ}C)$
		Added the Symbol to "Power supply current in Sleep modes" $I_{\rm CCSRCH},I_{\rm CCSRCL}$
		Changed the Conditions of I _{CCSMAIN} in "Power supply current in Sleep modes" "SMCR:LPMSS=0" is added
39		Changed the Value of "Power supply current in Sleep modes" I_{CCSPLL} Max:15mA \rightarrow 13m A (T _A = +105°C)
		$\begin{split} &I_{CCSMAIN} \\ &Typ: \ 1.0mA \rightarrow 0.9m \ A \ (T_A = +25^{\circ}C) \\ &Max: \ 7mA \rightarrow 4m \ A \ (T_A = +105^{\circ}C) \\ &I_{CCSSUB} \end{split}$
		Typ: $0.08\text{mA} \rightarrow 0.04\text{m A}$ (T _A = +25°C) Max: 4mA $\rightarrow 2.5\text{m A}$ (T _A = +105°C)
		Added the Symbol to "Power supply current in Timer modes" I_{CCTPLL}
40		Changed the Conditions of $I_{CCTMAIN}$, I_{CCTRCH} in "Power supply current in Timer modes" "SMCR:LPMSS=0" is added
		Added the Symbol
		$\begin{tabular}{lllllllllllllllllllllllllllllllllll$
41		Typ: 5 μ A, Max: 15 μ A, Remarks: nothing \rightarrow
		Typ: 5μ A, Max: -, Remarks: $T_A = +25^{\circ}$ C Typ: -, Max: 12.5 μ A, Remarks: $T_A = +105^{\circ}$ C
		Changed the condition of "Flash Write/Erase current" $I_{CCFLASH}$ Typ: 12.5mA, Max: 20mA, Remarks: nothing \rightarrow
		Typ: 12.5mA, Max: -, Remarks: $T_A = +25^{\circ}C$ Typ: -, Max: 20mA, Remarks: $T_A = +105^{\circ}C$

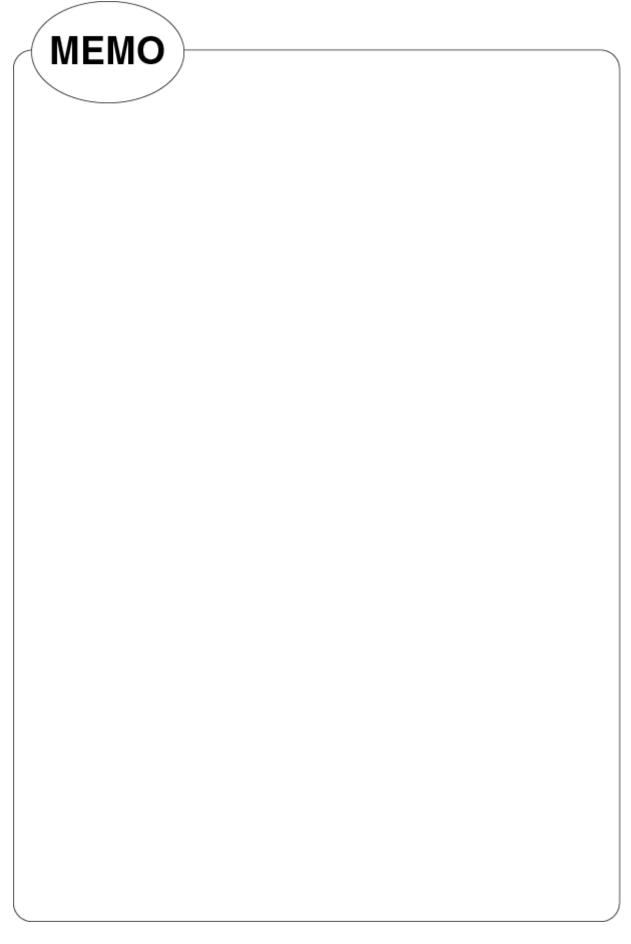
Page	Section	Change Results
41	3. DC Characteristics (1) Current Rating	Changed the annotation *2 The power supply current is measured with a 4MHz external clock connected to the Main oscillator and a 32kHz external clock connected to the Sub oscillator. → When Flash is not in Power-down / reset mode, I _{CCFLASHPD} must be added to the Power supply current. The power supply current is measured with a 4MHz external clock connected to the Main oscillator and a 32kHz external clock connected to the Sub oscillator. The current for "On Chip Debugger" part is not included.
43	3. DC Characteristics(2) Pin Characteristics	Added the Symbol for DEBUG I/F pin V _{OLD}
44		Changed the Pin name of "Input capacitance" Other than Vcc, Vss, AVcc, AVss, AVRH, P08_m \rightarrow Other than C, Vcc, Vcc, Vss, DVcc, DVss, AVRH, P08_m Deleted the annotation "I _{OH} and I _{OL} are target value." Added the annotation "In the case of driving stepping motor directly or high current outputs, set "1" to the bit in the Port High Drive Register (PHDRnn:HDx="1")."
45	4. AC Characteristics (1) Main Clock Input Characteristics	Added the figure (t_{CYLH}) when using the external clock
46	4. AC Characteristics(2) Sub Clock Input Characteristics	Added the figure (t_{CYLL}) when using the crystal oscillator clock
47	4. AC Characteristics(3) Built-in RC OscillationCharacteristics	Added "RC clock stabilization time"
48	4. AC Characteristics(5) Operating Conditions of PLL	Changed the Value of "PLL input clock frequency"Max: 16MHz \rightarrow 8MHzChanged the Symbol of "PLL oscillation clock frequency" $f_{PLLO} \rightarrow f_{CLKVCO}$ Added Remarks to "PLL oscillation clock frequency"Added " PLL phase jitter" and the figure

Page	Section	Change Results
48	4. AC Characteristics(6) Reset Input	Added the figure for reset input time (t _{RSTL})
	4. AC Characteristics (8) USART Timing	Changed the condition $(V_{CC} = AV_{CC} = DV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = DV_{SS} = 0V,$ $T_A = -40^{\circ}\text{C to} + 105^{\circ}\text{C})$ \rightarrow $(V_{CC} = AV_{CC} = DV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = DV_{SS} = 0V,$
50		(V(C = AV(C = D V(C = 2.) V to 5.0 V, Vss = AVss = D Vss = 0 V, $T_A = -40^{\circ}$ C to + 105°C, $C_L = 50$ pF) Changed the HARDWARE MANUAL "MB96690 series HARDWARE MANUAL" → "MB96600 series HARDWARE MANUAL"
51		Changed the figure for "Internal shift clock mode"
53	4. AC Characteristics (10) I ² C timing	Added parameter, "Noise filter" and an annotation *5 for it Added t _{SP} to the figure
	5. A/D Converter	Added "Analog impedance"
54	(1) Electrical Characteristics for	Added "Variation between channels"
51	the A/D Converter	Added the annotation
	5. A/D Converter	Deleted the unit "[Min]" from approximation formula of
55	(2) Accuracy and Setting of the A/D Converter Sampling Time	Sampling time
56	5. A/D Converter (3) Definition of A/D Converter Terms	Changed the Description and the figure "Linearity" \rightarrow "Nonlinearity" "Differential linearity error" \rightarrow "Differential nonlinearity error" Changed the Description Linearity error: Deviation of the line between the zero-transition point (0b000000000 $\leftarrow \rightarrow$ 0b000000001) and the full-scale transition point (0b111111110 $\leftarrow \rightarrow$ 0b111111111) from the actual conversion characteristics. \rightarrow Nonlinearity error: Deviation of the actual conversion characteristics from a straight line that connects the zero transition point (0b000000000 $\leftarrow \rightarrow$ 0b000000001) to the full-scale transition point (0b111111110 $\leftarrow \rightarrow$ 0b111111111). Added the Description "Zero transition voltage" "Full scale transition voltage"
58	6. High Current Output Slew Rate	$ \begin{array}{l} \mbox{Changed the condition} \\ (V_{CC} = AV_{CC} = 2.7V \mbox{ to } 5.5V, DV_{CC} = 4.5V \mbox{ to } 5.5V, V_{SS} = AV_{SS} \\ = DV_{SS} = 0V, T_A = -40^\circ\mbox{C to } + 105^\circ\mbox{C}) \\ \rightarrow \\ (V_{CC} = AV_{CC} = DV_{CC} = 2.7V \mbox{ to } 5.5V, V_{SS} = AV_{SS} = DV_{SS} = 0V, \\ T_A = -40^\circ\mbox{C to } + 105^\circ\mbox{C}) \\ \hline \mbox{Changed the Symbol and figure} \\ t_{R2}, t_{F2}, V_{OL2} \\ \rightarrow \\ t_{R30}, t_{F30}, V_{OL30} \end{array} $

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Page	Section	Change Results	
	7. Low Voltage Detection	Added the Value of "Power supply voltage change rate"	
	Function Characteristics	Max: +0.004 V/µs	
		Added "Hysteresis width" (V _{HYS})	
59		Added "Stabilization time" (T _{LVDSTAB})	
		Added "Detection delay time" (t _d)	
		Deleted the Remarks	
		Added the annotation *1, *2	
60		Added the figure for "Hysteresis width"	
00		Added the figure for "Stabilization time"	
	8. Flash Memory Write/Erase	Changed the Value of "Sector erase time"	
	Characteristics	Added "Security Sector" to "Sector erase time"	
		Changed the Parameter	
		"Half word (16 bit) write time"	
		\rightarrow	
		"Word (16-bit) write time"	
61		Changed the Value of "Chip erase time"	
01		Changed the Remarks of "Sector erase time"	
		Excludes write time prior to internal erase	
		\rightarrow	
		Includes write time prior to internal erase	
		Added the Note and annotation *1	
		Deleted "(targeted value)" from title "Write/Erase cycles and	
		data hold time"	
62 to 64	■EXAMPLE CHARACTERISTICS	Added a section	





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